

Industrial fully integrated H-bridge motor driver



Product status link
STSPIN3P21
STSPIN3P22
STSPIN3P23



Features

- Supply voltage from 4 V to 16 V with extended range up to 32 V
- Scalable current ratings:
 - STSPIN3P21: 82 mΩ (per leg), 15 A
 - STSPIN3P22: 45 mΩ (per leg), 23 A
 - STSPIN3P23: 30 mΩ (per leg), 35 A
- 3 V CMOS compatible inputs
- Undervoltage shutdown
- Overvoltage clamp
- Thermal shutdown
- Cross-conduction protection
- Current and power limitation
- Very low standby power consumption
- Protection against loss of ground and loss of V_{CC}
- PWM operation up to 25 kHz
- MultiSense monitoring functions
 - Analog motor current feedback
 - Chip temperature monitoring
- MultiSense diagnostic functions
 - Output short to ground detection
 - Thermal shutdown indication
 - OFF-state open-load detection
 - High-side power limitation indication
 - Low-side overcurrent shutdown indication
 - Output short to V_{CC} detection
- Output protected against short to ground and short to V_{CC}
- Standby mode
- Half bridge operation

Applications

- Stage lighting
- Factory automation
- ATM and money handling machines
- Textile machines
- Home appliances
- Robotics
- Brushed DC motors
- Solenoids

Description

STSPIN3P2 is a full-bridge product series that expands the capability of STSPIN family for low-voltage DC motors.

STSPIN3P2 integrates efficient and robust technologies from STMicroelectronics to provide reliable solutions at an unrivaled level for industrial applications. The level of protection offered by STSPIN3P2 is excellent, with a comprehensive set of features. The device is protected from overvoltage, undervoltage, overtemperature, and cross conduction. Furthermore, the design combines simplicity with advanced monitoring and optimized motor control.

The input signals INA and INB can interface directly with the microcontroller to select the motor direction and the brake condition. Two selection pins, SEL0 and SEL1, are available to access information on the MultiSense pin and PH_OUT pin.

The MultiSense pin enables monitoring the motor current by delivering a current proportional to the motor current value and provides the diagnostic feedback. The PH_OUT pin provides feedback on the OUT status, confirming that the motor operates correctly. The PWM, with a frequency of up to 25 kHz, allows control of the motor speed under all conditions. In all cases, a low-level state on the PWM pin turns off both the LSA and LSB switches.

The STSPIN3P2 series is assembled in a QFN 6×6 mm triple-pad 26+2L package equipped with three exposed islands for optimized dissipation performance. This package is designed for harsh industrial environments and offers improved thermal performance due to exposed die pads.

1 Block diagram

Figure 1. Block diagram

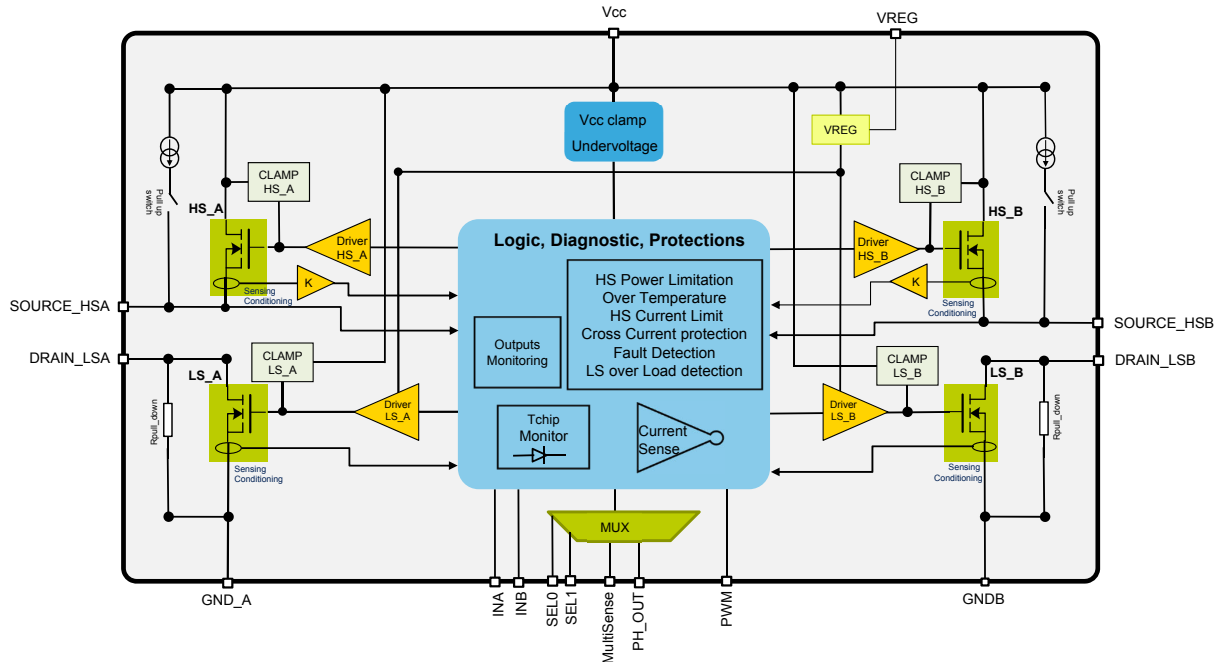


Table 1. Block description

Name	Description
Logic control	Allows the turn-on and the turn-off of the high-side and the low-side switches according to the Table 16.
Undervoltage	Shuts down the device for battery voltage below (4 V).
High-side and low-side driver	Drives the gate of the concerned switch to allow a proper $R_{DS(on)}$ for the leg of the bridge.
High-side current limitation	Limits the motor current in case of short circuit.
High-side and low-side overtemperature protection	In case of overload that increase the junction temperature, it shuts down the concerned driver to prevent degradation and to protect the die.
Low-side overcurrent detector	Detects when low-side current exceeds shutdown current and latches off the concerned low side.
Fault detection	Signalizes an abnormal condition of the switch (output shorted to ground or output shorted to battery) by feedback on the MultiSense.
High-side power limitation	Limits the power dissipation of the high-side driver inside safe range in case of short to ground condition.
T_{chip} warning	Provides a warning signal of the chip temperature by feedback on the MultiSense.
VREG	Internal voltage regulator that provides the supply for the gates of the low-side switches.
Output monitoring	Provides feedback of OUTA and OUTB state in ON state and OFF state.

2 Pin description

Figure 2. Pin description (bottom view)

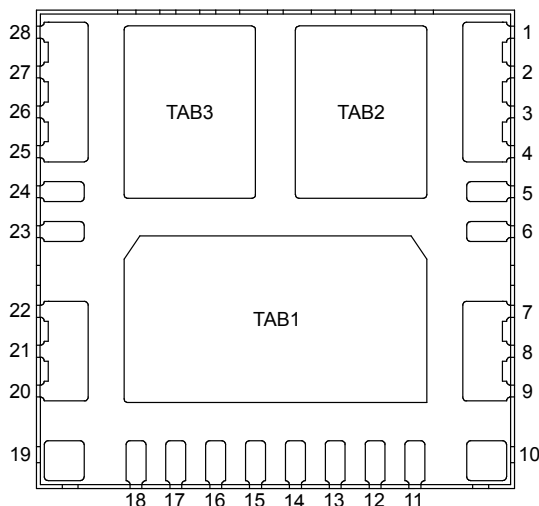


Table 2. Pin definition and function

Pin	Symbol	Function
1, 2, 3, 4	GNDB	Source of low-side switch B.
5, 6, TAB2	DRAIN_LSB	Drain of low-side switch B.
7, 8, 9	SOURCE_HSB	Source of high-side switch B.
10, 19, TAB1	VCC	Power supply voltage.
11	INB	Counterclockwise input.
12	PH_OUT	Output of phase OUT diagnostic feedback.
13	SEL1	Address the MultiSense multiplexer.
14	SEL0	Address the MultiSense multiplexer.
15	MultiSense	Output of current sense and diagnostic feedback.
16	PWM	PWM input. Voltage controlled input pin with hysteresis, CMOS compatible. Gates of low-side Power MOSFETs. Active high.
17	VREG	Internal voltage regulator that provides the supply for the gates of the internal low-side switches.
18	INA	Clockwise input.
20, 21, 22	SOURCE_HSA	Source of high-side switch A.
23, 24, TAB3	DRAIN_LSA	Drain of low-side switch A.
25, 26, 27, 28	GNDA	Source of low-side switch A.

Table 3. Suggested connection for unused pin

Connection/ pin	MultiSense	NC	SOURCE_HSx	DRAIN_LSx	INx, PWM, SELx	VREG	PH_OUT
Floating	Not allowed	X ⁽¹⁾	X ⁽¹⁾	X ⁽¹⁾	X ⁽¹⁾	Not allowed	X ⁽¹⁾
To ground	Through 1 kΩ resistor	X ⁽¹⁾	Not allowed	X ⁽¹⁾	Through 15 kΩ resistor	Through 220 Ω resistor + 100 nF capacitor	X ⁽¹⁾

1. X: do not care.

3 Device Ratings

3.1 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in Table 1 may cause permanent damage to the device. Exposure to maximum rating conditions for extended periods may affect device reliability.

All voltages are referred to GND.

Table 4. Absolute maximum ratings

Symbol	Parameter	Notes	Value	Unit
V_{CC}	Supply voltage		-0.3 to 32	V
I_{max}	DC output current (continuous)		Internally limited	A
DRAIN_LSA, DRAIN_LSB, SOURCE_HSA, SOURCE_HSB	OUT clamp voltage		-0.3 to V_{CC}	V
I_R	Reverse output current (continuous) ⁽¹⁾	STSPIN3P21	-6.6	A
		STSPIN3P22	-9	A
		STSPIN3P23	-16	A
IN_A, IN_B, SEL0, SEL1, PWM	Input current		-1 to 10	mA
PH_OUT	Phase out pin		7	V
MultiSense	DC output current ($V_{GND} = V_{CC}$ and $V_{MultiSense} < 0$ V)		10	mA
	DC output current ($V_{GND} = V_{CC}$ and $V_{MultiSense} < 0$ V)		-20	mA
	DC output operating voltage (continuous)		4	V
VREG	Internal low side gate driver regulator	STSPIN3P21	-0.3 to 8	V
		STSPIN3P22, STSPIN3P23	-0.3 to 8.2	V
T_J	Operating junction temperature range		-40 to 150	°C
T_{stg}	Storage temperature range		-55 to 150	°C

1. Based on the internal wires capability.

3.2 Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Notes	Min.	Typ.	Max	Unit
V _{CC}	Supply voltage		4		16	V
C _{CC}	VCC filtering capacitor			4.7		μF
C _{DEC}	VCC decoupling capacitor			100		nF
VREG	Internal low-side gate driver regulator	V _{CC} > 7 V		7		V
		V _{CC} < 7 V		V _{CC}		V
C _{REG}	VREG capacitor			100		nF
R _{REG}	VREG resistor			220		Ω
V _{IN}	Logic inputs voltage (INA, INB, PWM, SEL0, SEL1)		0		5	V
f _{PWM}	PWM frequency				25	kHz
T _J	Operating junction temperature range		-40		150	°C

3.3 ESD protections

Table 6. ESD protections

Symbol unit	Parameter	Value	Unit
Electrostatic discharge (Human body model: R = 1.5 kΩ; C = 100 pF)	INA, INB, PWM, MultiSense, SEL0, SEL1, VREG, PH_OUT	2	kV
	V _{CC} , DRAIN_LSA, DRAIN_LSB, SOURCE_HSA, SOURCE_HSB	4	

3.4 Thermal data

Table 7. Thermal data

Symbol	Parameter	Max. value	Unit
R _{thJB}	Thermal resistance, junction-to-board (measured on 6L PCB)	8.3	°C/W
R _{thJA}	Thermal resistance, junction-to-ambient	See Table 19	°C/W

4 Electrical characteristics

Testing conditions: $7\text{ V} < V_{CC} < 16\text{ V}$, SOURCE_HSA shorted to DRAIN_LSA = OUTA, SOURCE_HSB shorted to DRAIN_LSB = OUTB, $-40\text{ °C} < T_J < 150\text{ °C}$, unless otherwise specified.

For Table 11: $V_{CC} = 13\text{ V}$, $R_{LOAD} = 3.7$ (STSPIN3P21), $R_{LOAD} = 3.25$ (STSPIN3P22), $R_{LOAD} = 2.6$ (STSPIN3P23), DRAIN_LSA = OUTA, SOURCE_HSB shorted to DRAIN_LSB = OUTB, $-40\text{ °C} < T_J < 150\text{ °C}$, unless otherwise specified.

Table 8. Supply and supply monitoring

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
I _S	Supply current	Standby: INA = INB = PWM = 0, SEL0,1 = 0, T _J = 25 °C, V _{CC} = 13 V			1	μA
		Standby: INA = INB = PWM = 0, SEL0,1 = 0, T _J = 125 °C, V _{CC} = 13 V			3	μA
		Off-state (no standby): INA = INB = PWM = 0, V _{CC} = 13 V, SEL0 = SEL1 = 5 V, T _J = 125 °C			3	mA
		On-state: INA or INB = 5 V, PWM = 5 V, no load V _{CC} = 13 V			3	mA
t _{D_STBY}	Standby mode blanking time	V _{CC} = 13 V, INA = INB = PWM = 0 V, SEL1 or SEL0 from 5 V to 0 V		300	500	μs
R _{ONHS}	STSPIN3P21 Static high-side resistance	I _{OUTx} = 3.5 A, T _J = 25 °C		32		mΩ
		I _{OUTx} = 3.5 A, T _J = -40 °C to 150 °C			70	
		V _{CC} = 4 V, I _{OUTx} = 3.5 A, T _J = 25 °C		35		
R _{ONLS}	STSPIN3P21 Static low-side resistance	I _{OUTx} = 3.5 A, V _{CC} ≥ 10 V, T _J = 25 °C		50		mΩ
		I _{OUTx} = 3.5 A, V _{CC} ≥ 10 V, T _J = -40 °C to 150 °C			110	
		V _{CC} = 4 V, I _{OUTx} = 3.5 A, T _J = 25 °C		96		
R _{ONHS}	STSPIN3P22 Static high-side resistance	I _{OUTx} = 4 A, T _J = 25 °C		25		mΩ
		I _{OUTx} = 4 A, T _J = -40 °C to 150 °C			60	
		V _{CC} = 4 V, I _{OUTx} = 4 A, T _J = 25 °C		28		
R _{ONLS}	STSPIN3P22 Static low-side resistance	I _{OUTx} = 4 A, V _{CC} ≥ 10 V, T _J = 25 °C		20		mΩ
		I _{OUTx} = 4 A, V _{CC} ≥ 10 V, T _J = -40 °C to 150 °C			40	
		V _{CC} = 4 V, I _{OUTx} = 4 A, T _J = 25 °C		30		
R _{ONHS}	STSPIN3P23 Static high-side resistance	I _{OUTx} = 5 A, T _J = 25 °C		16		mΩ
		I _{OUTx} = 5 A, T _J = -40 °C to 150 °C			33	
		V _{CC} = 4 V, I _{OUT} = 5 A, T _J = 25 °C		18		
R _{ONLS}	STSPIN3P23	I _{OUTx} = 5 A, V _{CC} ≥ 10 V, T _J = 25 °C		13		mΩ

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
R _{ONLS}	Static low-side resistance	I _{OUTx} = 5 A, V _{CC} ≥ 10 V, T _J = - 40 °C to 150 °C			25	mΩ
		V _{CC} = 4 V, I _{OUT} = 5 A, T _J = 25 °C		23		
V _f	High-side free-wheeling diode forward voltage	I _{OUTx} = -4 A, T _J = 150 °C			0.7	V
I _{L(off)}	Standby output current of one leg	T _J = 25 °C, V _{CC} = 13 V, SEL0 = SEL1 = 0 INA = INB = PWM = 0, V _{OUTx} = 0			1	μA
		T _J = 125 °C, V _{CC} = 13V, SEL0 = SEL1 = 0, INA = INB = PWM = 0, V _{OUTx} = 0			3	μA

Table 9. Logic inputs (INA, INB, PWM, SEL0, SEL1)

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
V _{IL}	Input low level voltage				0.9	V
V _{IH}	Input high level voltage		2.1			V
V _{IHYST}	Input hysteresis voltage		0.2			V
V _{ICL}	Input clamp voltage (except SEL1)	I _{IN} = 1 mA	6		8.5	V
		I _{IN} = -1 mA		-0.7		V
V _{SELCL}	Input clamp voltage SEL1	I _{SEL} = 1 mA	9		12	V
		I _{SEL} = -1 mA		-0.7		
I _{INH}	Input current	V _{IN} = 2.1 V			10	μA
I _{INL}	Input current	V _{IN} = 0.9 V	1			μA

Table 10. Logic outputs (PH_OUT) open drain output

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
V _{OL_PH}	Output low level voltage	R _{pu} = 10 kΩ			0.4	V
t _{DELAYr}	Phase out delay time on rising OUT	R _{pu} = 10 kΩ From 90% of OUTx to 90% of PH_OUT INA = INB = PWM = 0 V, V _{OUTx} = 4 V, SEL0 = 1, SEL1 = 0 (SEL0 = 0, SEL1 = 1) (see Figure 11)			1.5	μs
t _{DELAYf}	Phase out delay time on falling OUT	R _{pu} = 10 kΩ From 10% of OUTx to 10% of PH_OUT INA = INB = PWM = 0 V, V _{OUTx} = 4 V, SEL0 = 1, SEL1 = 0 (SEL0 = 0, SEL1 = 1) (see Figure 11)			1.5	μs
t _{delay2}	Phase out delay time from SELx to OUTPUT	R _{pu} = 10 kΩ SEL0 = from 0 to 1 or from 1 to 0, up to 90% or 10% respectively (see Figure 12)			1.5	μs

Table 11. Switching

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
t_{on}	Turn-on time	PWM = 0 V, SELx = 5 V (no standby), INx from 0 to 5 V, V_{OUTx} to 90% of V_{CC} (see Figure 6)		57	110	μ s
t_{off}	Turn-off time STSPIN3P21 and STSPIN3P23	PWM = 0 V, SELx = 5 V (no standby), INx from 5 V to 0 V, V_{OUTx} to 10% of V_{CC} (see Figure 6)		38	110	μ s
t_{off}	Turn-off time STSPIN3P22	PWM = 0 V, SELx = 5 V (no standby), INx from 5 V to 0 V, V_{OUTx} to 10% of V_{CC} (see Figure 6)		38	60	μ s
t_r	Rise time STSPIN3P21 and STSPIN3P22	INx = SELx = 5 V (no standby), PWM from 5V to 0V, V_{OUTx} from 10% to 80%			0.8	μ s
t_r	Rise time STSPIN3P22	INx = SELx = 5 V (no standby), PWM from 5V to 0V, V_{OUTx} from 10% to 80%			0.9	μ s
t_f	Fall time STSPIN3P21 and STSPIN3P22	INx = SELx = 5 V (no standby), PWM from 0V to 5V, V_{OUTx} from 90% to 20%			0.9	μ s
t_f	Fall time STSPIN3P22	INx = SELx = 5 V (no standby), PWM from 0V to 5V, V_{OUTx} from 90% to 20%			0.8	μ s
t_{cross}	Low-side turn-on delay time	(see Figure 7)	40		300	μ s

Table 12. Protections and diagnostics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
V_{USD}	Undervoltage shutdown	V_{CC} falling			4	V
$V_{USDreset}$	Undervoltage shutdown	V_{CC} rising			5	V
$V_{USDhyst}$	Undervoltage shutdown hysteresis			0.3		V
I_{LIM_HSD}	High-side current limitation STSPIN3P21	$V_{CC} = 13$ V	15		30	A
		4 V < $V_{CC} < 16$ V			30	A
I_{SD_LSD}	Shutdown LS current STSPIN3P21		18		36	A
I_{LIM_HSD}	High-side current limitation STSPIN3P22	$V_{CC} = 13$ V	23		46	A
		4 V < $V_{CC} < 16$ V			46	A
I_{SD_LSD}	Shutdown LS current STSPIN3P22		28		56	A
I_{LIM_HSD}	High-side current limitation STSPIN3P23	$V_{CC} = 13$ V	35		70	A
		4 V < $V_{CC} < 16$ V			70	A
I_{SD_LSD}	Shutdown LS current STSPIN3P23		42		84	A
t_{SD_LSD}	Low-side shutdown time	INA = INB = 0, PWM = 5 V, $I_{OUT} = I_{SD_LSD}$ (see Figure 8)		2		μ s
V_{CL_HSD}	High-side clamp voltage (V_{CC} to $V_{OUTx} = 0$ V)	$I_{OUT} = 100$ mA, $t_{clamp} = 1$ ms, $I_{clamp} = 100$ mA	36	38	45	V

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
V _{CL_LSD}	Low-side clamp voltage (V _{OUTx} = V _{CC} to GND)	I _{OUT} = 100 mA, t _{clamp} = 1 ms, I _{clamp} = 100 mA	36	38	45	V
V _{CL}	Total clamp voltage from V _{CC} to GND	I _{OUT} = 100 mA, t _{clamp} = 1 ms, I _{clamp} = 100 mA	36	38	45	V
T _{TSD}	High-side and low-side thermal shutdown temperature		150	175	200	°C
T _{TR}	Thermal reset temperature		135			°C
T _{HYST}	Thermal hysteresis (T _{TSD} - T _{TR})			7		°C
ΔT _{J_SD}	Dynamic temperature			70		°C
V _{OL}	OFF-state open-load voltage detection threshold	INA = INB = 0, PWM = 0 V _{SEL0} = 5 V, V _{SEL1} = 0 V for CHA, V _{SEL0} = 0 V, V _{SEL1} = 5 V for CHB	2	3	4	V
I _{L(off2)}	OFF-state output sink current	INA = INB = 0, V _{OUTx} = V _{OL} , PWM = 0, SEL0 = 1, SEL1 = 0 for CHA, SEL0 = 0, SEL1 = 1 for CHB	-100		-10	μA
t _{DSTKON}	OFF-state diagnostic delay time from falling edge of INPUT	INA = 5 V to 0 V, INB = 0, PWM = 0, V _{SEL0} = 5 V, V _{SEL1} = 0 V, I _{OUTA} = 0 A, V _{OUTA} = 4 V (see Figure 4)	40	160	300	μs
t _{D_VOL}	OFF-state diagnostic delay time from rising edge of V _{OUT}	INA = INB = 0, PWM = 0, V _{OUTx} = 0 V to 4 V, SEL0 = 1, SEL1 = 0 for CHA, SEL0 = 0, SEL1 = 1 for CHB (see Figure 13)		1.2	10	μs
t _{Latch_RST}	Minimum input reset time	V _{INx} = 5 V to 0 V (on HSDx fault) or V _{INx} = 0 V to 5 V (on LSDx Fault) (see Figure 7)	15			μs

Table 13. MultiSense - STSPIN3P21

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
V _{MultiSense_CL}	MultiSense clamp voltage	SEL0 = SEL1 = 0, I _{SENSE} = -1 mA		7		V
		SEL0 = SEL1 = 0, I _{SENSE} = 1 mA	-9	-8	-7	
K _{OL}	I _{OUT} /I _{MultiSense}	I _{OUTx} = 0.05 A, V _{MultiSense} = 0.5 V	5135	7900	10665	
K ₀	I _{OUT} /I _{MultiSense}	I _{OUTx} = 0.3 A, V _{MultiSense} = 0.5 V	5925	7900	9875	
K ₁	I _{OUT} /I _{MultiSense}	I _{OUTx} = 1 A, V _{MultiSense} = 3.5 V	6715	7900	9085	
K ₂	I _{OUT} /I _{MultiSense}	I _{OUTx} = 3.5 A, V _{MultiSense} = 3.5 V	7347	7900	8453	
K ₃	I _{OUT} /I _{MultiSense}	I _{OUTx} = 6 A, V _{MultiSense} = 3.5 V	7347	7900	8453	
dK _{OL} /K _{OL}	Analog sense current drift	I _{OUTx} = 0.05 A, V _{MultiSense} = 0.5 V	-30%		30%	
dK ₀ /K ₀	Analog sense current drift	I _{OUTx} = 0.3 A, V _{MultiSense} = 0.5 V	-25%		25%	
dK ₁ /K ₁	Analog sense current drift	I _{OUTx} = 1 A, V _{MultiSense} = 3.5 V	-10%		10%	
dK ₂ /K ₂	Analog sense current drift	I _{OUTx} = 3.5 A, V _{MultiSense} = 3.5 V	-6%		6%	
dK ₃ /K ₃	Analog sense current drift	I _{OUTx} = 6 A, V _{MultiSense} = 3.5 V	-5%		5%	
I _{MultiSense0}	MultiSense leakage current	INA = INB = PWM = 0 V, SEL0 = SEL1 = 0 V,			0.5	μA

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
I _{MultiSense0}	MultiSense leakage current	standby				
		INA = INB = 5 V, PWM = 0 V, legX diagnostic selected, I _{OUTx} = 0 A			5	μA
		PWM = 0 V, HSx OFF, legX diagnostic selected: • SEL0 = 5 V, SEL1 = 0 V, INA = 0 V, INB = 5 V, I _{OUTB} = 3.5 A, • SEL0 = 0 V, SEL1 = 5 V, INB = 0 V, INA = 5 V, I _{OUTA} = 3.5 A			5	μA
V _{SENSEH}	MultiSense output voltage in fault condition	9 V < V _{CC} < 16 V, R _{SENSE} = 0.7 kΩ, V _{OUT} = 4 V	5		7.5	V
V _{OUT_MSD} ⁽¹⁾	Output voltage for MultiSense shutdown	INA = SEL0 = 5V, INB = SEL1 = 0 V, R _{SENSE} = 2.7 kΩ, I _{OUTx} = 3.5 A		5		V
V _{SENSE_SAT}	MultiSense saturation voltage	V _{CC} = 7 V, SEL0 = INA = 5 V, INB = SEL1 = 0 V, R _{SENSE} = 10 kΩ, I _{OUTA} = 6 A, T _J = -40 °C	4.8			V
I _{SENSE_SAT} ⁽¹⁾	MultiSense saturation current	V _{CC} = 7 V, V _{MultiSense} = 3.5 V, SEL0 = 5V, INA = 5 V, INB = SEL1 = 0 V, T _J = 150 °C	2			mA
I _{OUT_SAT} ⁽¹⁾	Output saturation current	V _{CC} = 13 V, V _{MultiSense} = 3.5 V, INA = SEL0 = 5 V, INB = SEL1 = 0 V, T _J = 150 °C	8			A
I _{SENSEH}	MultiSense current in fault condition	9 V < V _{CC} < 16 V, V _{MultiSense} = 5 V, MultiSense in fault condition	7		12	mA
Chip temperature analog warning						
T _{CASE_Warning}	MultiSense = V _{SENSEH}	SEL1 = SEL0 = 5 V, MultiSense = V _{SENSEH}		140		°C
MultiSense timings (multiplexer transition times), R_{SENSE} = 1 kΩ						
t _{D_AtoB}	MultiSense transition delay from legA to legB	INA = INB = 5 V, PWM = 0 V, SEL0 = 5 V to 0 V, SEL1 = 0 V to 5 V, I _{OUTA} = 200 mA, I _{OUTB} = 6 A			20	μs
t _{D_BtoA}	MultiSense transition delay from legB to legA	INA = INB = 5 V, PWM = 0 V, SEL0 = 0 V to 5 V, SEL1 = 5 V to 0 V, I _{OUTB} = 200 mA, I _{OUTA} = 6 A			20	μs
MultiSense timings (Current sense mode)						
t _{DSENSE1H}	Current sense settling time from rising edge of V _{SELx}	V _{INA} = V _{PWM} = 5 V, V _{INB} = 0 V, V _{SEL0} = 0 V to 5 V, R _{SENSE} = 0.7 kΩ, R _L = 3.7 Ω, V _{SEL1} = 0 V			60	μs
t _{DSENSE1L}	Current sense disable time from falling edge of V _{SELx}	V _{INA} = V _{PWM} = 5 V, V _{INB} = 0 V,			20	μs

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
		$V_{SEL0} = 5\text{ V to }0\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.7\ \Omega$, $V_{SEL1} = 0\text{ V}$				
$t_{DSENSE2H}$	Current sense settling time from rising edge of V_{INx}	$V_{SEL0} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL1} = 0\text{ V}$, $V_{INA} = 0\text{ V to }5\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.7\ \Omega$			150	μs
$t_{DSENSE2L}$	Current sense disabling time from falling edge of V_{INx}	$V_{SEL0} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL1} = 0\text{ V}$, $V_{INA} = 5\text{ V to }0\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.7\ \Omega$			20	μs

1. Parameter specified by design and evaluated by characterization, not tested in production.

Table 14. MultiSense - STSPIN3P22

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$V_{MultiSense_CL}$	MultiSense clamp voltage	$SEL0 = SEL1 = 0$, $I_{SENSE} = -1\text{ mA}$		7		V
		$SEL0 = SEL1 = 0$, $I_{SENSE} = 1\text{ mA}$	-9	-8	-7	
K_{OL}	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 0.05\text{ A}$, $V_{MultiSense} = 0.5\text{ V}$	6825	10500	14175	
K_0	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 0.3\text{ A}$, $V_{MultiSense} = 0.5\text{ V}$	7875	10500	13125	
K_1	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 1\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	8925	10500	12075	
K_2	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 4\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	9765	10500	11235	
K_3	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 7\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	9765	10500	11235	
dK_{OL}/K_{OL}	Analog sense current drift	$I_{OUTx} = 0.05\text{ A}$, $V_{MultiSense} = 0.5\text{ V}$	-30%		30%	
dK_0/K_0	Analog sense current drift	$I_{OUTx} = 0.3\text{ A}$, $V_{MultiSense} = 0.5\text{ V}$	-25%		25%	
dK_1/K_1	Analog sense current drift	$I_{OUTx} = 1\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	-10%		10%	
dK_2/K_2	Analog sense current drift	$I_{OUTx} = 4\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	-6%		6%	
dK_3/K_3	Analog sense current drift	$I_{OUTx} = 7\text{ A}$, $V_{MultiSense} = 3.5\text{ V}$	-5%		5%	
$I_{MultiSense0}$	MultiSense leakage current	$INA = INB = PWM = 0\text{ V}$, $SEL0 = SEL1 = 0\text{ V}$, standby			0.5	μA
		$INA = INB = 5\text{ V}$, $PWM = 0\text{ V}$, legX diagnostic selected, $I_{OUTx} = 0\text{ A}$			5	μA
		$PWM = 0\text{ V}$, HSx OFF, legX diagnostic selected: • $SEL0 = 5\text{ V}$, $SEL1 = 0\text{ V}$, $INA = 0\text{ V}$, $INB = 5\text{ V}$, $I_{OUTB} = 4\text{ A}$, • $SEL0 = 0\text{ V}$, $SEL1 = 5\text{ V}$, $INB = 0\text{ V}$, $INA = 5\text{ V}$, $I_{OUTA} = 4\text{ A}$			5	μA
V_{SENSEH}	MultiSense output voltage in fault condition	$9\text{ V} < V_{CC} < 16\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $V_{OUT} = 4\text{ V}$	5		7.5	V
$V_{OUT_MSD}^{(1)}$	Output voltage for MultiSense shutdown	$INA = SEL0 = 5\text{ V}$, $INB = SEL1 = 0\text{ V}$, $R_{SENSE} = 2.7\text{ k}\Omega$, $I_{OUTx} = 4\text{ A}$		5		V
V_{SENSE_SAT}	MultiSense saturation voltage	$V_{CC} = 7\text{ V}$, $SEL0 = INA = 5\text{ V}$, $INB = SEL1 = 0\text{ V}$, $R_{SENSE} = 10\text{ k}\Omega$, $I_{OUTA} = 7\text{ A}$, $T_J = -40\text{ }^\circ\text{C}$	4.8			V

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$I_{SENSE_SAT}^{(1)}$	MultiSense saturation current	$V_{CC} = 7\text{ V}$, $V_{MultiSense} = 3.5\text{ V}$, $SEL0 = 5\text{ V}$, $INA = 5\text{ V}$, $INB = SEL1 = 0\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$	2			mA
$I_{OUT_SAT}^{(1)}$	Output saturation current	$V_{CC} = 7\text{ V}$, $V_{MultiSense} = 3.5\text{ V}$, $INA = SEL0 = 5\text{ V}$, $INB = SEL1 = 0\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$	13			A
$I_{SENSEH}^{(1)}$	MultiSense current in fault condition	$9\text{ V} < V_{CC} < 16\text{ V}$, $V_{MultiSense} = 5\text{ V}$, MultiSense in fault condition	7		12	mA
Chip temperature analog warning						
$T_{CASE_Warning}$	MultiSense = V_{SENSEH}	$SEL1 = SEL0 = 5\text{ V}$, MultiSense = V_{SENSEH}		140		$^\circ\text{C}$
MultiSense timings (multiplexer transition times), $R_{SENSE} = 1\text{ k}\Omega$						
t_{D_AtoB}	MultiSense transition delay from legA to legB	$INA = INB = 5\text{ V}$, $PWM = 0\text{ V}$, $SEL0 = 5\text{ V to } 0\text{ V}$, $SEL1 = 0\text{ V to } 5\text{ V}$, $I_{OUTA} = 200\text{ mA}$, $I_{OUTB} = 6\text{ A}$			20	μs
t_{D_BtoA}	MultiSense transition delay from legB to legA	$INA = INB = 5\text{ V}$, $PWM = 0\text{ V}$, $SEL0 = 0\text{ V to } 5\text{ V}$, $SEL1 = 5\text{ V to } 0\text{ V}$, $I_{OUTB} = 200\text{ mA}$, $I_{OUTA} = 6\text{ A}$			20	μs
MultiSense timings (Current sense mode)						
$t_{DSENSE1H}$	Current sense settling time from rising edge of V_{SELx}	$V_{INA} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL0} = 0\text{ V to } 5\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.25\text{ }\Omega$, $V_{SEL1} = 0\text{ V}$			60	μs
$t_{DSENSE1L}$	Current sense disable time from falling edge of V_{SELx}	$V_{INA} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL0} = 5\text{ V to } 0\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.25\text{ }\Omega$, $V_{SEL1} = 0\text{ V}$			20	μs
$t_{DSENSE2H}$	Current sense settling time from rising edge of V_{INx}	$V_{SEL0} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL1} = 0\text{ V}$, $V_{INA} = 0\text{ V to } 5\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.25\text{ }\Omega$			150	μs
$t_{DSENSE2L}$	Current sense disabling time from falling edge of V_{INx}	$V_{SEL0} = V_{PWM} = 5\text{ V}$, $V_{INB} = 0\text{ V}$, $V_{SEL1} = 0\text{ V}$, $V_{INA} = 5\text{ V to } 0\text{ V}$, $R_{SENSE} = 0.7\text{ k}\Omega$, $R_L = 3.25\text{ }\Omega$			20	μs

1. Parameter specified by design and evaluated by characterization, not tested in production.

Table 15. MultiSense - STSPIN3P23

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$V_{MultiSense_CL}$	MultiSense clamp voltage	$SEL0 = SEL1 = 0$, $I_{SENSE} = -1\text{ mA}$		7		V
		$SEL0 = SEL1 = 0$, $I_{SENSE} = 1\text{ mA}$	-9	-8	-7	

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
K_{OL}	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 0.05 \text{ A}$, $V_{MultiSense} = 0.5 \text{ V}$	7800	12000	16200	
K_0	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 0.3 \text{ A}$, $V_{MultiSense} = 0.5 \text{ V}$	9000	12000	15000	
K_1	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 1 \text{ A}$, $V_{MultiSense} = 3.5 \text{ V}$	10200	12000	13800	
K_2	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 5 \text{ A}$, $V_{MultiSense} = 4 \text{ V}$	11160	12000	12840	
K_3	$I_{OUT}/I_{MultiSense}$	$I_{OUTx} = 10 \text{ A}$, $V_{MultiSense} = 3.5 \text{ V}$	11160	12000	12840	
dK_{OL}/K_{OL}	Analog sense current drift	$I_{OUTx} = 0.05 \text{ A}$, $V_{MultiSense} = 0.5 \text{ V}$	-30%		30%	
dK_0/K_0	Analog sense current drift	$I_{OUTx} = 0.3 \text{ A}$, $V_{MultiSense} = 0.5 \text{ V}$	-25%		25%	
dK_1/K_1	Analog sense current drift	$I_{OUTx} = 1 \text{ A}$, $V_{MultiSense} = 3.5 \text{ V}$	-10%		10%	
dK_2/K_2	Analog sense current drift	$I_{OUTx} = 5 \text{ A}$, $V_{MultiSense} = 3.5 \text{ V}$	-6%		6%	
dK_3/K_3	Analog sense current drift	$I_{OUTx} = 10 \text{ A}$, $V_{MultiSense} = 3.5 \text{ V}$	-5%		5%	
$I_{MultiSense0}$	MultiSense leakage current	INA = INB = PWM = 0 V, SEL0 = SEL1 = 0 V, standby			0.5	μA
		INA = INB = 5 V, PWM = 0 V, legX diagnostic selected, $I_{OUTx} = 0 \text{ A}$			5	μA
		PWM = 0 V, HSx OFF, legX diagnostic selected: • SEL0 = 5 V, SEL1 = 0 V, INA = 0 V, INB = 5 V, $I_{OUTB} = 5 \text{ A}$, • SEL0 = 0 V, SEL1 = 5 V, INB = 0 V, INA = 5 V, $I_{OUTA} = 5 \text{ A}$			5	μA
V_{SENSEH}	MultiSense output voltage in fault condition	$9 \text{ V} < V_{CC} < 16 \text{ V}$, $R_{SENSE} = 0.7 \text{ k}\Omega$, $V_{OUT} = 4 \text{ V}$	5		7.5	V
$V_{OUT_MSD}^{(1)}$	Output voltage for MultiSense shutdown	INA = SEL0 = 5V, INB = SEL1 = 0 V, $R_{SENSE} = 2.7 \text{ k}\Omega$, $I_{OUTx} = 5 \text{ A}$		5		V
V_{SENSE_SAT}	MultiSense saturation voltage	$V_{CC} = 7 \text{ V}$, SEL0 = INA = 5 V, INB = SEL1 = 0 V, $R_{SENSE} = 10 \text{ k}\Omega$, $I_{OUTA} = 10 \text{ A}$, $T_J = -40 \text{ }^\circ\text{C}$	4.8			V
$I_{SENSE_SAT}^{(1)}$	MultiSense saturation current	$V_{CC} = 7 \text{ V}$, $V_{MultiSense} = 3.5 \text{ V}$, SEL0 = 5V, INA = 5 V, INB = SEL1 = 0 V, $T_J = 150 \text{ }^\circ\text{C}$	2			mA
$I_{OUT_SAT}^{(1)}$	Output saturation current	$V_{CC} = 7 \text{ V}$, $V_{MultiSense} = 3.5 \text{ V}$, INA = SEL0 = 5 V, INB = SEL1 = 0 V, $T_J = 150 \text{ }^\circ\text{C}$	20			A
I_{SENSEH}	MultiSense current in fault condition	$9 \text{ V} < V_{CC} < 16 \text{ V}$, $V_{MultiSense} = 5 \text{ V}$, MultiSense in fault condition	7		12	mA
Chip temperature analog warning						
$T_{CASE_Warning}$	MultiSense = V_{SENSEH}	SEL1 = SEL0 = 5 V, MultiSense = V_{SENSEH}		140		$^\circ\text{C}$
MultiSense timings (multiplexer transition times), $R_{SENSE} = 1 \text{ k}\Omega$						
t_{D_AtoB}	MultiSense transition delay from legA to legB	INA = INB = 5 V, PWM = 0 V,			20	μs

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
		SEL0 = 5 V to 0 V, SEL1 = 0 V to 5 V, I _{OUTA} = 200 mA, I _{OUTB} = 6 A				
t _{D_BtoA}	MultiSense transition delay from legB to legA	INA = INB = 5 V, PWM = 0 V, SEL0 = 0 V to 5 V, SEL1 = 5 V to 0 V, I _{OUTB} = 200 mA, I _{OUTA} = 6 A			20	μs
MultiSense timings (Current sense mode)						
t _{DSENSE1H}	Current sense settling time from rising edge of V _{SELx}	V _{INA} = V _{PWM} = 5 V, V _{INB} = 0 V, V _{SEL0} = 0 V to 5 V, R _{SENSE} = 0.7 kΩ, R _L = 2.6 Ω, V _{SEL1} = 0 V			60	μs
t _{DSENSE1L}	Current sense disable time from falling edge of V _{SELx}	V _{INA} = V _{PWM} = 5 V, V _{INB} = 0 V, V _{SEL0} = 5 V to 0 V, R _{SENSE} = 0.7 kΩ, R _L = 2.6 Ω, V _{SEL1} = 0 V			20	μs
t _{DSENSE2H}	Current sense settling time from rising edge of V _{INx}	V _{SEL0} = V _{PWM} = 5 V, V _{INB} = 0 V, V _{SEL1} = 0 V, V _{INA} = 0 V to 5 V, R _{SENSE} = 0.7 kΩ, R _L = 2.6 Ω			150	μs
t _{DSENSE2L}	Current sense disabling time from falling edge of V _{INx}	V _{SEL0} = V _{PWM} = 5 V, V _{INB} = 0 V, V _{SEL1} = 0 V, V _{INA} = 5 V to 0 V, R _{SENSE} = 0.7 kΩ, R _L = 2.6 Ω			20	μs

1. Parameter specified by design and evaluated by characterization, not tested in production.

Figure 3. Current sense timings (current sense mode)

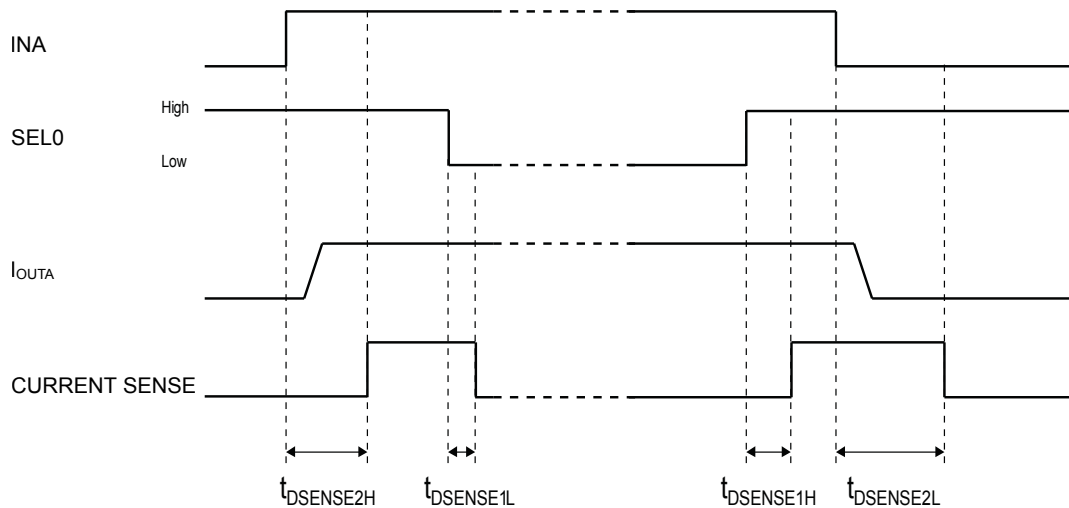


Figure 4. t_{DSTKON}

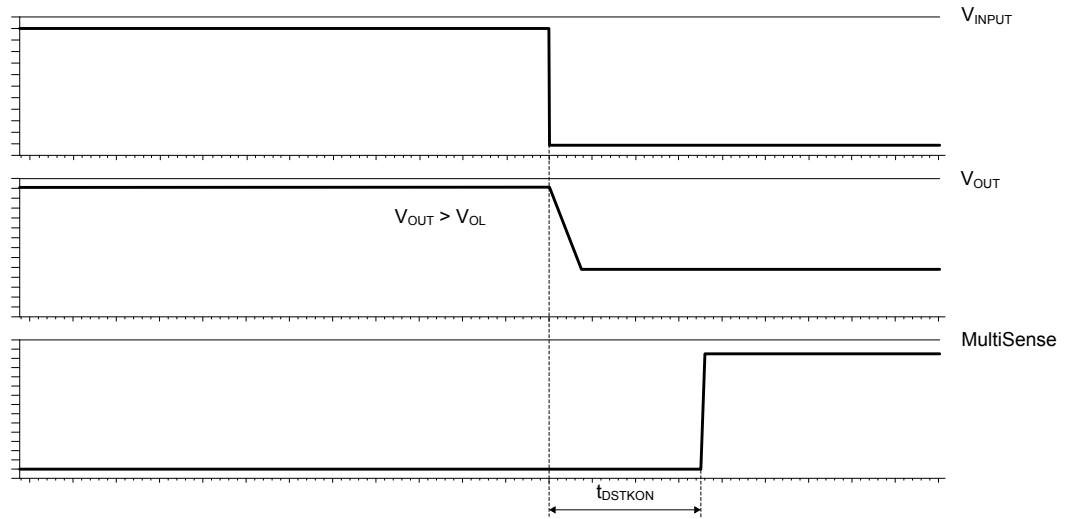


Figure 5. Definition of the low-side switching times

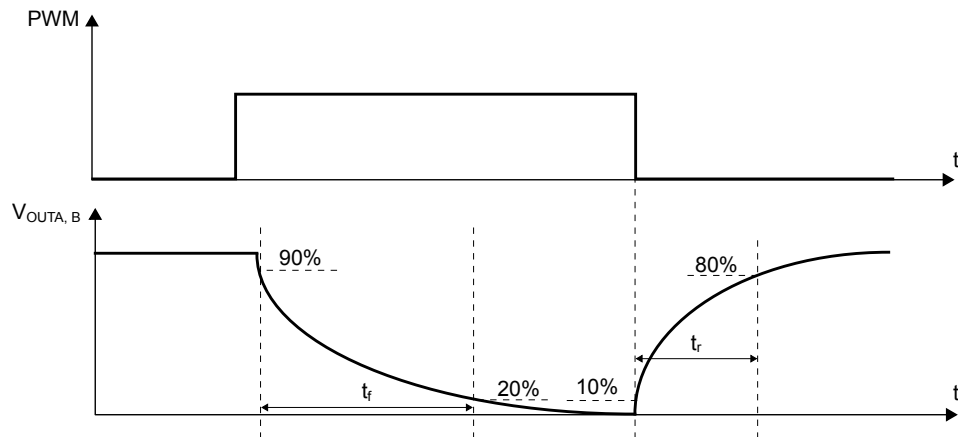


Figure 6. Definition of the high-side switching times

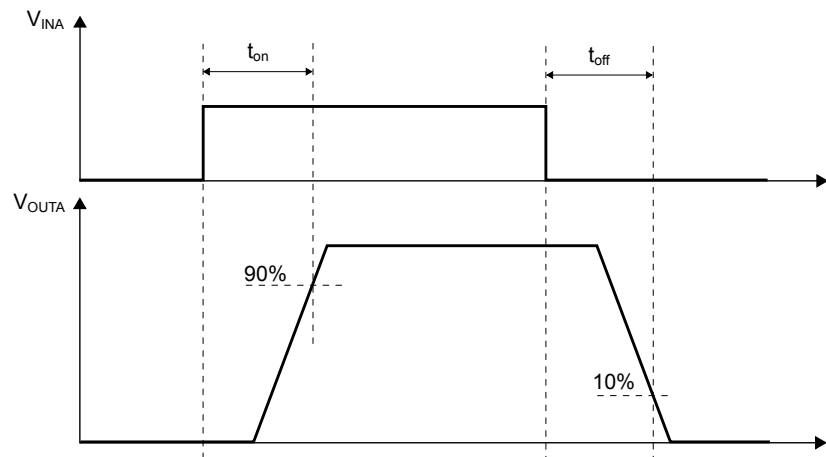


Figure 7. Low-side turn-on delay time

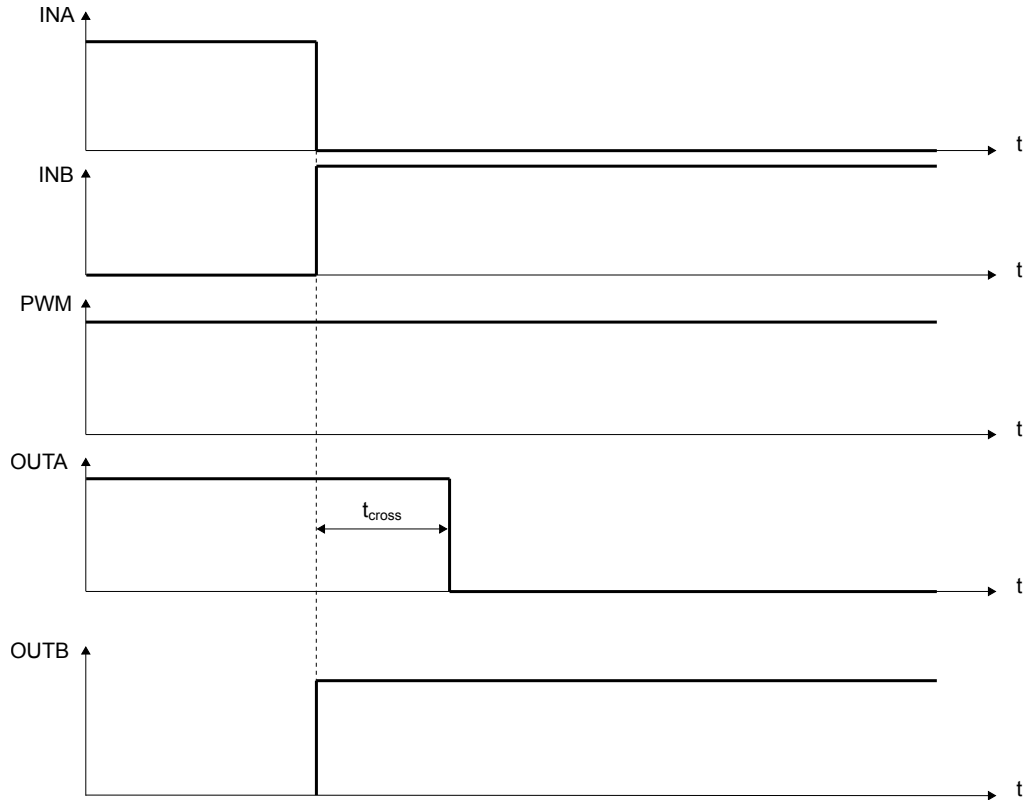


Figure 8. Time to shutdown for the low-side driver

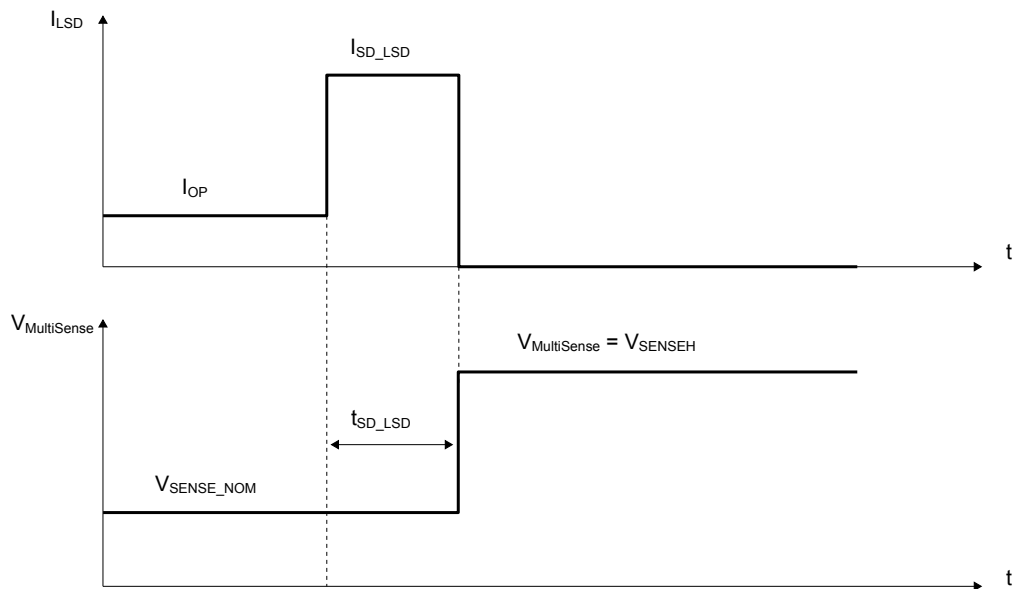


Figure 9. Input reset time for HSD-fault unlatch

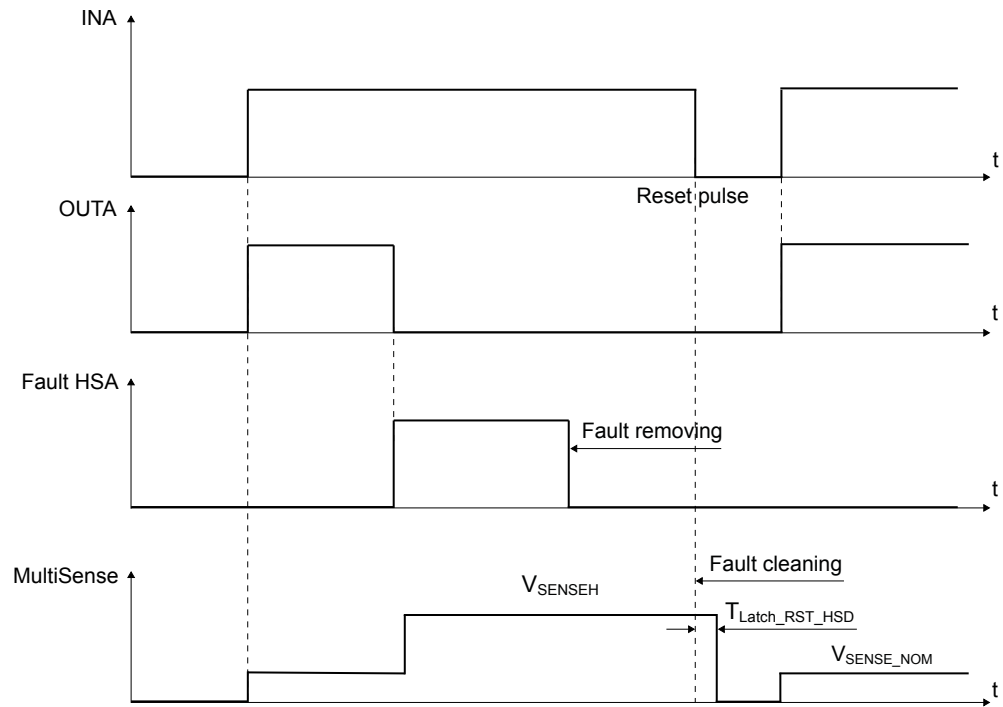


Figure 10. Input reset time for LSD-fault unlatch

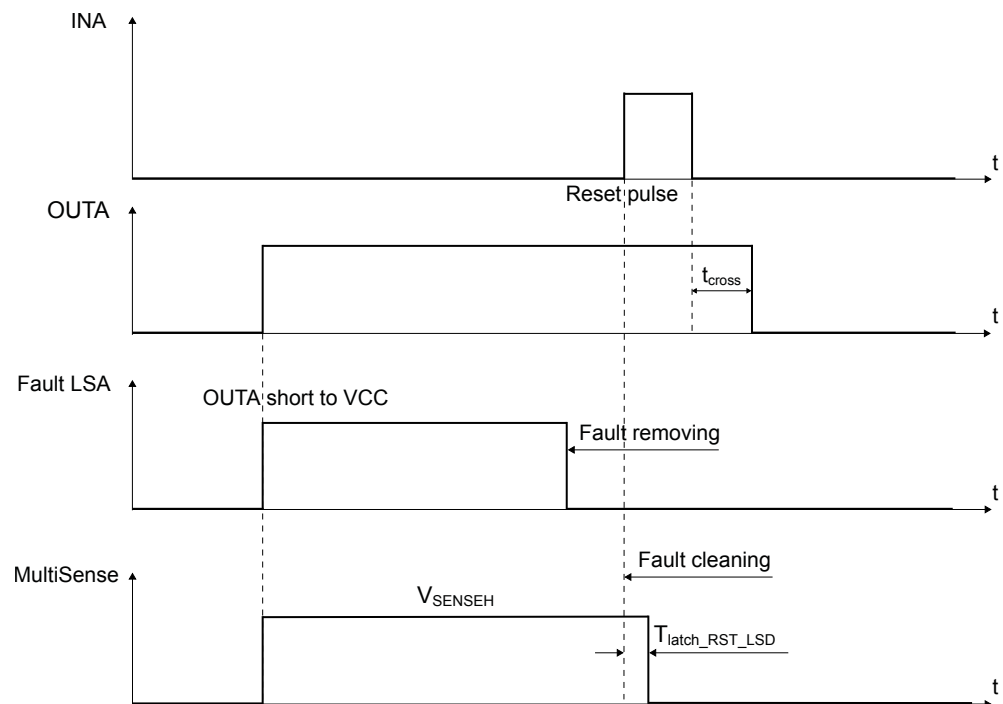


Figure 11. PH_OUT delay time on out switch

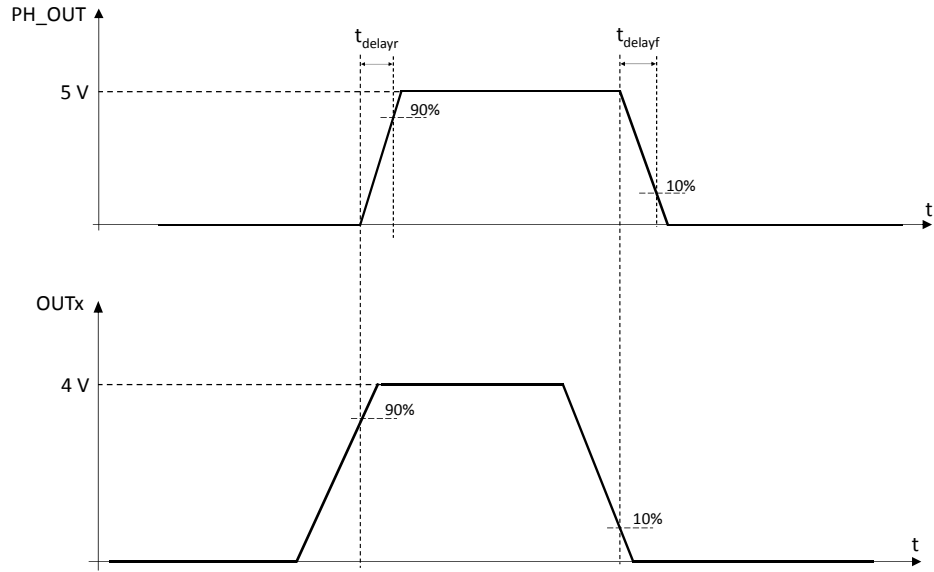
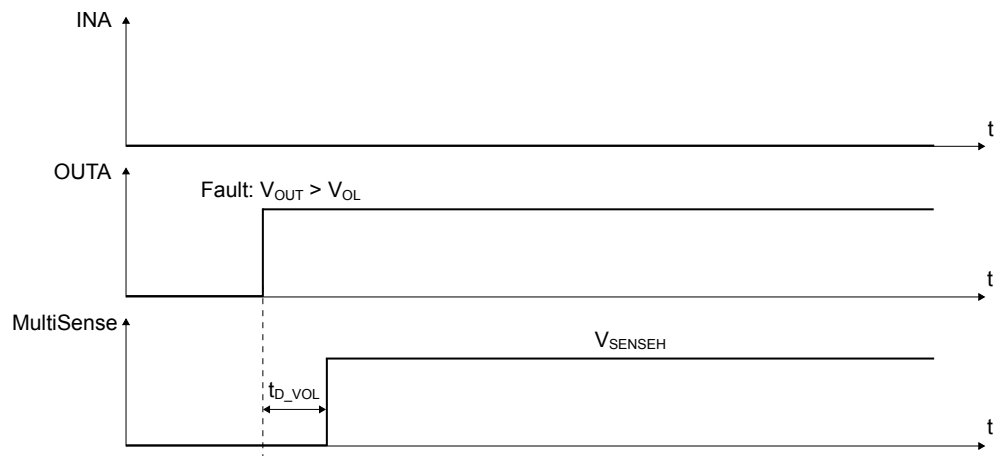


Figure 12. PH_OUT delay time on SELx change



Figure 13. OFF-state diagnostic delay time from rising edge of V_{OUT} (t_{D_VOL})



5 Operative conditions and diagnostic

The input signals INA and INB can directly interface the microcontroller to select the motor direction and the brake to V_{CC} condition.

Two selection pins (SEL0 and SEL1) to address the information are available on the MultiSense to the microcontroller. The MultiSense pin allows monitoring the motor current by delivering a current proportional to the motor current value and provides the diagnostic feedback and case temperature according to the implemented truth table [Table 16](#).

The PH_OUT pin provides feedback on the OUTA and OUTB state for safety-relevant functions.

The PWM allows controlling the speed of the motor in all possible conditions or selecting the brake to GND condition.

In all cases, a low-level state on the PWM pin turns off both the LSA and LSB switches.

Table 16. Truth table: operative condition and diagnostic

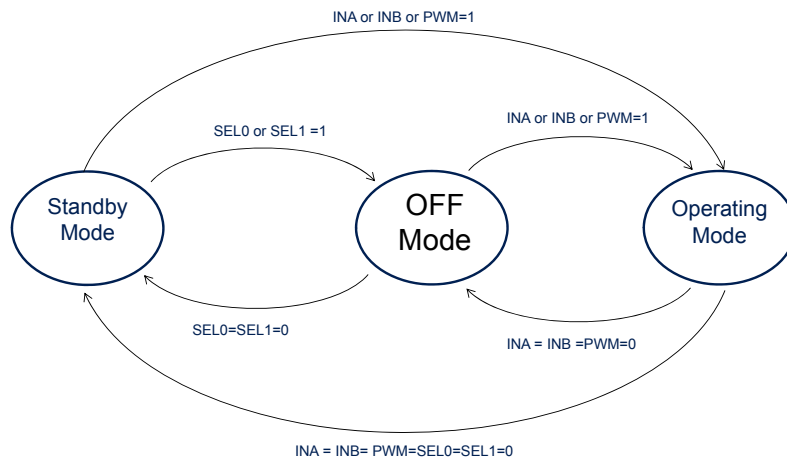
SEL0	SEL1	INA	INB	PWM	HB status	PH_OUT	MultiSense	Diagnostic MultiSense = V_{SENSEH}	Comments
1	0	1	0	1	Clock	MONITOR A	Current sense ON HSA	ON state HSA protection triggered, HSA latched off	
		0	1	1	Counterclock	MONITOR A	HiZ	ON state LSA protection triggered, LSA latched off	
		1	1	0	BRAKE VCC	MONITOR A	Current sense ON HSA	ON state HSA protection triggered, HSA latched off	
		0	0	1	BRAKE GND	MONITOR A	HiZ	ON state LSA protection triggered, LSA latched off	
		1	0	0	HSA ON	MONITOR A	Current sense ON HSA	ON state HSA protection triggered, HSA latched off	
		0	1	0	HSB ON	MONITOR A	HiZ		
		0	0	0	OFF	MONITOR A	HiZ	$V_{OUTA} > V_{OL}$: NO open- load in full bridge configuration, OUTA shorted to VCC in half bridge configuration	Pull up on OUTB - diagnostic in off state
		1	1	1	BRAKE VCC	MONITOR A	Current sense ON HSA	ON state HSA protection triggered, HSA latched off	
0	1	1	0	1	Clock	MONITOR B	HiZ	ON state LSB protection triggered, LSB latched off	
		0	1	1	Counterclock	MONITOR B	Current sense ON HSB	ON state HSB protection triggered, HSB latched off	
		1	1	0	BRAKE VCC	MONITOR B	Current sense ON HSB	ON state HSB protection triggered, HSB latched off	
		0	0	1	LSB ON/ LSA OFF	MONITOR B	HiZ	ON state LSB protection triggered, LSB latched off	Half bridge on LSB - Pull up on OUTB
		1	0	0	HSA ON	MONITOR B	HiZ		

SEL0	SEL1	INA	INB	PWM	HB status	PH_OUT	MultiSense	Diagnostic MultiSense = V _{SENSEH}	Comments
0	1	0	1	0	HSB ON	MONITOR B	Current sense ON HSB	ON state HSB protection triggered, HSB latched off	
		0	0	0	OFF	MONITOR B	HiZ	V _{OUTB} > V _{OL} : NO open- load in full bridge configuration, OUTB shorted to VCC in half bridge configuration	Pull up on OUTA - diagnostic in off state
		1	1	1	BRAKE VCC	MONITOR B	Current sense ON HSB	ON state HSB protection triggered, HSB latched off	
1	1	1	0	1	Clock	MONITOR A	HiZ	TCHIP WARNING	
		0	1	1	Counterclock	MONITOR A	HiZ	TCHIP WARNING	
		1	1	0	BRAKE VCC	MONITOR A	HiZ	TCHIP WARNING	
		0	0	1	LSA ON/LSB OFF	MONITOR A	HiZ	ON state protection triggered, LSA latched off	Half bridge on LSA - Pull up on OUTA
		1	0	0	HSA ON	MONITOR A	HiZ	TCHIP WARNING	
		0	1	0	HSB ON	MONITOR A	HiZ	TCHIP WARNING	
		0	0	0	OFF	MONITOR A	HiZ	Full bridge configuration: OUTA shorted to VCC, V _{OUTA} > V _{OL}	
		1	1	1	BRAKE VCC	MONITOR A	HiZ	TCHIP WARNING	
0	0	1	0	1	Clock	MONITOR B	HiZ		
		0	1	1	Counterclock	MONITOR B	HiZ		
		1	1	0	BRAKE VCC	MONITOR B	HiZ		
		0	0	1	BRAKE GND	MONITOR B	HiZ	ON state LSB protection triggered, LSB latched off	
		1	0	0	HSA ON	MONITOR B	HiZ		
		0	1	0	HSB ON	MONITOR B	HiZ		
		0	0	0	STAND BY	HiZ	HiZ		
		1	1	1	BRAKE VCC	MONITOR B	HiZ		

Note:

1. SOURCE_HSA shorted to DRAIN_LSA = OUTA, SOURCE_HSB shorted to DRAIN_LSB = OUTB.
2. In brake to GND condition (INA = INB = L, PWM = H) settling the pin SEL1 = 1 AND SEL0 = 0 or SEL1 = 1 AND SEL0 = 1 it is possible to keep one leg in high-Z for half bridge configuration and diagnostic.
3. When INA = INB = PWM = SEL0 = SEL1 = 0 the device enters in standby after T_{DSTBY}.

Figure 14. State diagram



6 Protections

6.1 Power limitation (high-side driver)

The power limitation protection consists of an indirect measurement of the junction temperature swing ΔT_J through the direct measurement of the spatial temperature gradient on the device surface. As soon as ΔT_J exceeds the safety level of ΔT_{J_SD} , the Power MOSFET output is automatically shut off.

The protection prevents fast thermal transient effects and, consequently, reduces thermo-mechanical fatigue. When power limitation is reached, the device enters in latch mode and generates the fault flag on MultiSense = V_{senseH} when the faulty leg diagnostic is selected (please refer to the [Table 16](#)). The concerned high-side can be switched ON again by applying the reset pulse as described in [Figure 9](#).

6.2 Thermal shutdown (high-side and low-side)

In case the junction temperature of the device exceeds the maximum allowed threshold (typically 175 °C), it automatically switches off and the diagnostic indication is triggered on MultiSense (please refer to the [Table 16](#)). The device can switch on again as soon as: T_J drops below thermal reset temperature, then by applying the reset pulse as described in [Figure 9](#) or [Figure 10](#).

6.3 Current limitation and overcurrent detector

The device is equipped with an output current limiter in order to protect the silicon as well as the other components of the system (for example bonding wires, wiring harness, connectors, loads, etc.) from excessive current flow.

High-side current limitation: in case of short-circuit, overload or during load power-up, the output current is clamped to a safety level, I_{LIM_HSD} , by operating the output Power MOSFET in the active region.

Low side overcurrent detector: this protection senses the current flowing in the low side. If the current exceeds a safety level I_{SD_LS} , the device switches off after a filtering time t_{SD_LSD} .

In the case of fault conditions caused by power limitation or overtemperature or open load/short to VCC in OFF state, the fault is indicated by the MultiSense pin being internally switched to a “current limited” voltage source pulled to level V_{SENSEH} (please refer to the [Table 16](#)).

7 MultiSense operation

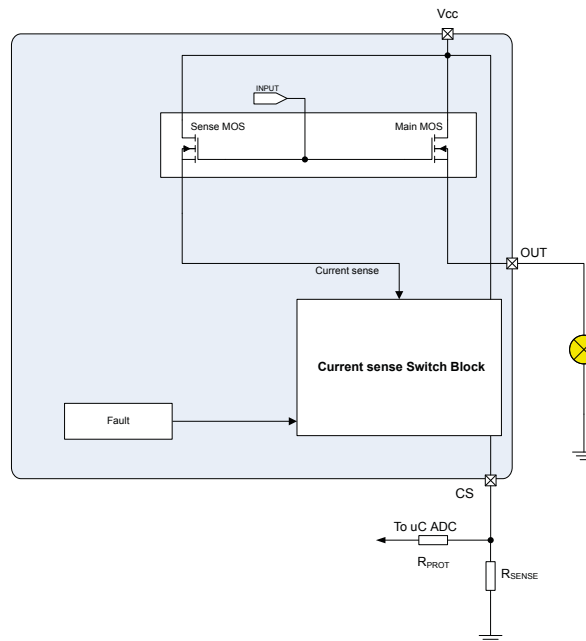
7.1 MultiSense analog current monitoring

Diagnostic information on device and load status is provided by an analog output pin (MultiSense) delivering the current mirror of high-side output current.

The signal is routed through an analog multiplexer, which is configured and controlled by means of SELx pins, according to the address map in MultiSense multiplexer addressing table.

7.1.1 Current sense signal generation principle

Figure 15. Current sense block diagram



Current sense

The output is capable of providing:

- Current mirror proportional to the load current in normal operation, delivering current proportional to the load according to a known ratio named K.
- Diagnostics flag in fault conditions delivering a current I_{SENSEH} converted into a voltage (V_{SENSEH}) by using an external sense resistor.

The current delivered by the current sense circuit, I_{SENSE} , can be easily converted into a voltage V_{SENSE} by using an external sense resistor, R_{SENSE} , allowing continuous load monitoring and abnormal condition detection.

Normal operation (channel ON, no fault)

While the device is operating in normal conditions (no fault intervention), V_{SENSE} calculation can be done using simple equations.

Current provided by MultiSense output: $I_{SENSE} = I_{OUT}/K$

Voltage on R_{SENSE} : $V_{SENSE} = R_{SENSE} \cdot I_{SENSE} = R_{SENSE} \cdot I_{OUT}/K$

Where:

- V_{SENSE} is the voltage measurable on the R_{SENSE} resistor
- I_{SENSE} is the current provided from current sense pin in current output mode
- I_{OUT} is the current flowing through output
- K factor represents the ratio between PowerMOS cells and SenseMOS cells; its spread includes geometric factor spread, current sense amplifier offset and process parameters spread of overall circuitry specifying the ratio between I_{OUT} and I_{SENSE} .

Current sense voltage saturation

In current sense mode the MultiSense pin has an intrinsic voltage dynamic range that depends on V_{CC} battery voltage. When the MultiSense pin exceeds the V_{SENSE_SAT} value, the current sense loses its linear behavior and saturates. At $V_{CC} = 13\text{ V}$, V_{SENSE_SAT} value is typically $\sim 7.5\text{ V}$, while the minimum $V_{SENSE_SAT_MIN} = 4.8\text{ V}$ is at $V_{CC} = 7\text{ V}$ and $T_J = -40\text{ }^\circ\text{C}$.

A proper dimensioning of R_{SENSE} value can ensure current sense linearity over the load current range. The Figure 16, Figure 17, Figure 18 show the V_{SENSE} behavior for several values of R_{SENSE} .

Figure 16. V_{SENSE} vs I_{LOAD} at $V_{CC} = 13\text{ V}$ (STSPIN3P21)

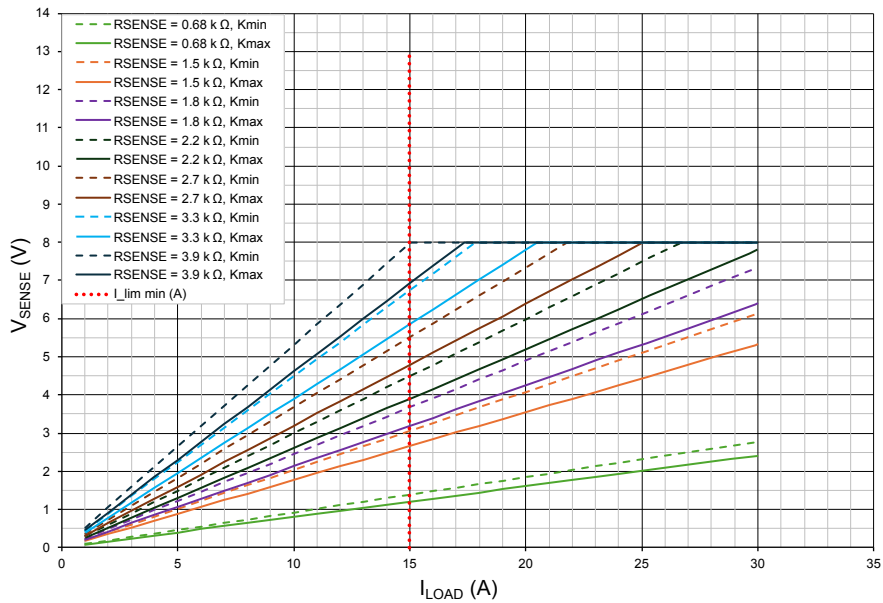


Figure 17. V_{SENSE} vs I_{LOAD} at $V_{CC} = 13\text{ V}$ (STSPIN3P22)

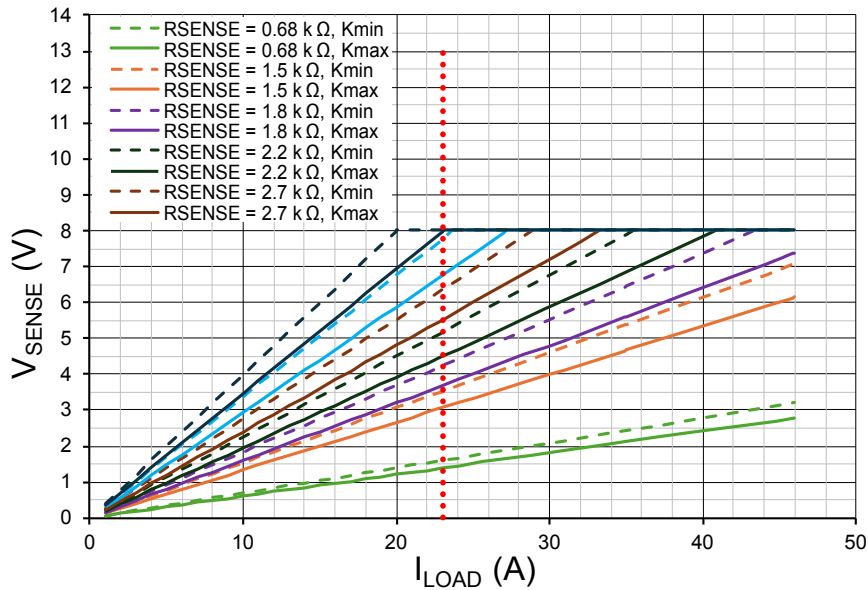
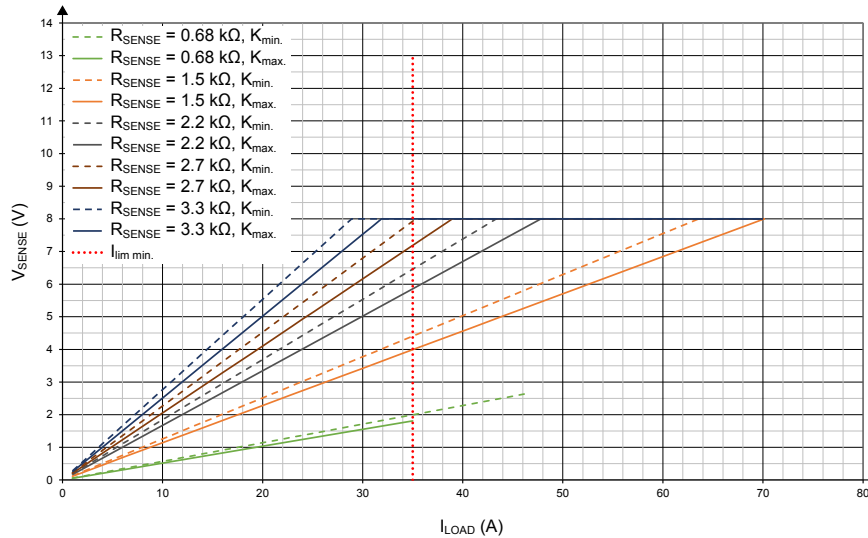


Figure 18. V_{SENSE} vs I_{LOAD} at $V_{CC} = 13\text{ V}$ (STSPIN3P23)



7.2 MultiSense diagnostics flag in fault conditions

Selecting MultiSense output as per Table 16, MultiSense pin delivers a current I_{SENSEH} converted to a voltage (V_{SENSEH}) by using an external sense resistor:

- Fault condition on **activated high-side** (in ON state) triggered by power limitation, overtemperature protection, where MultiSense output is selected as per Table 16 to high-side in fault state.
- Fault condition on **activated low-side** (in ON state) triggered by overcurrent shutdown, overtemperature protection, where MultiSense output is selected as per Table 16 to the same leg (of high-side) where low-side is in fault state.
- Short circuit to VCC on OUT in OFF state ($INA = INB = PWM = 0$).
- T_{CASE} warning: when T_{chip} exceeds $T_{CASE_Warning}$ (typ. 140 °C).

7.3 Diagnostic in off-state

The diagnostic in off-state operates when output is deactivated (it means $INA = INB = PWM = 0$). The detection is performed by reading the MultiSense output (V_{SENSEH} or HiZ) and also checking the PH_OUT status pin. The output to be monitored and internal pull-up are selectively switched through SEL0 and SEL1 as per [Table 16](#).

Pulling output voltage above the maximum open-load detection voltage ($V_{OL Max.}$) allows to detect short to VCC or open-load conditions before starting the motor.

8 VREG and Driver_LS block

The VREG pin is the output of an internal low drop voltage regulator. The VREG block is designed to power the driver of LS Power MOSFET and it allows a proper MOSFET transition.

An external capacitor $C_{REG} = 100 \text{ nF}$ and series resistor $R_{REG} = 220 \text{ } \Omega$ must be connected to the pin VREG that is needed to properly polarize the circuit (see [Figure 19](#)).

The VREG output voltage is $V_{REG} = 7 \text{ V}$ if $V_{CC} > 7 \text{ V}$, while $V_{REG} = V_{CC}$ if $V_{CC} < 7 \text{ V}$.

9 Output monitoring

The device features the possibility to provide a digital signal through the PH_OUT pin to let an external microcontroller read the OUT phase according to the [Table 16](#).

It allows the system to detect if a single Power MOSFET remains permanently ON or OFF independently from input state in both ON state and OFF state. The microcontroller selecting the input SEL0 and SEL1 according to the [Table 16](#) checks that the output state is consistent with input logic (INA, INB, and PWM) and provides the reaction of unwanted motor activation.

The detection of phase readout requires the internal pull-up and pull-down resistor RPU connecting the output (refer to the [Table 16](#)).

- During clockwise and counterclockwise motor activations, external R_{PULL_UP} is not needed.
- During brake to VCC, the microcontroller alternatively switches off one of the two high-side blocks and thanks to the embedded pull-down resistor the microcontroller can detect if the related high side is failing short through the PH_OUT pin.
- During brake to GND, the microcontroller alternatively switches off one of the two low-side blocks and thanks to the embedded pull-up the microcontroller can detect if the related low side is failing short through the PH_OUT pin.

Note: In brake to GND condition (INA = INB = L, PWM = H) settling the pins SEL1 and SEL0 according to [Table 16](#) it is possible to keep one leg in high-impedance to use the device in full half-bridge operation.

10 MCU I/Os protection

If a ground protection network is used and negative transients are present on the VCC line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line both to prevent the microcontroller I/O pins from latching-up and to protect the inputs.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

11 Typical application schematic

Figure 19. Typical application schematic

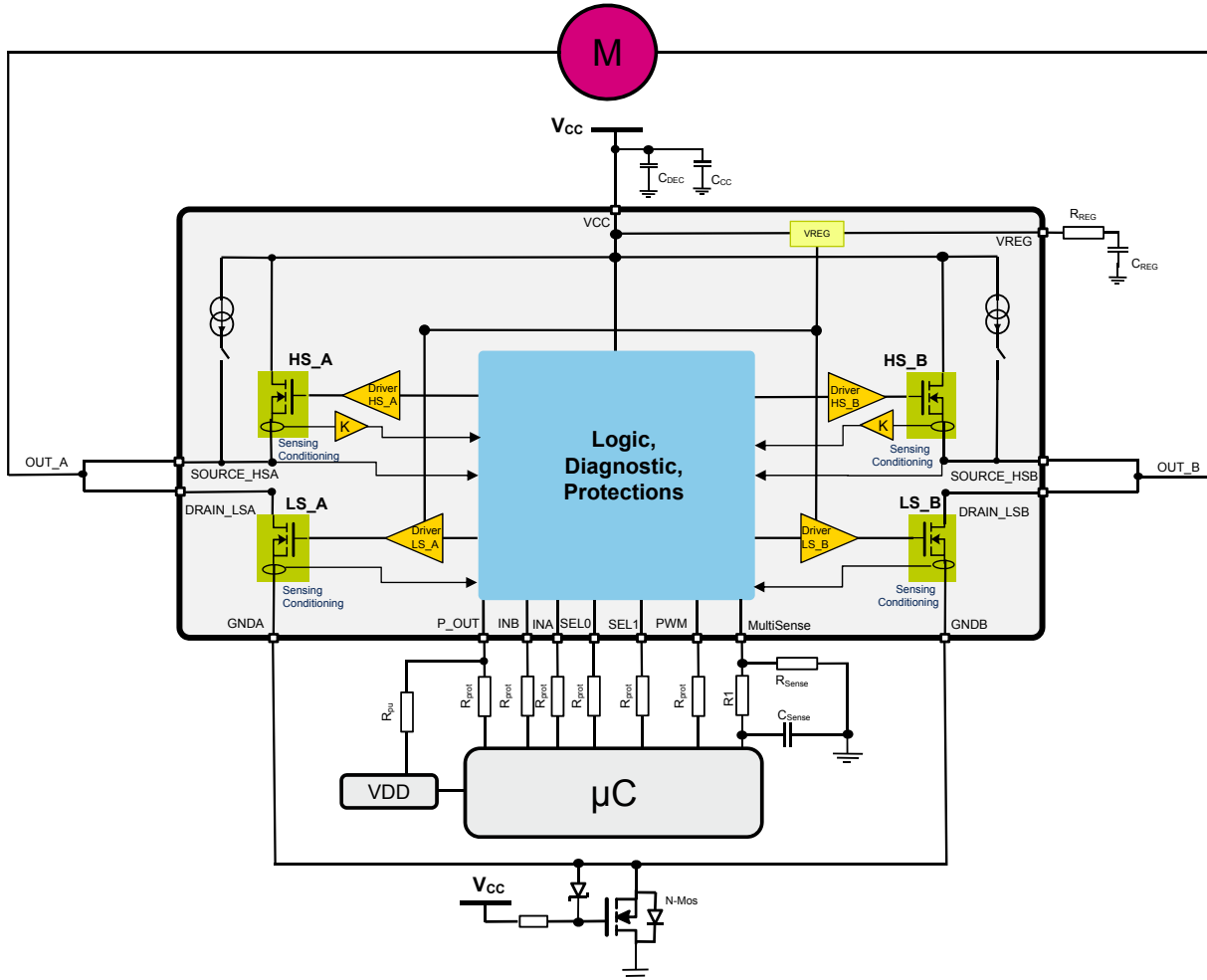


Table 17. Suggested external components

Component	Value
C_{DEC}	100 nF
C_{CC}	4.7 μ F
R_{REG}	220 Ω
C_{REG}	100 nF
R_{prot}	1.5 k Ω
R1	10 k Ω
R_{Sense}	0.7 k Ω
C_{Sense}	10 nF
R_{pu}	10 k Ω

12 Package and PCB thermal data

12.1 QFN 6x6 triple pad 26+2L PCB layout

Figure 20. QFN 6x6 26+2L PCB 8 cm², 2 layers (STSPIN3P23)

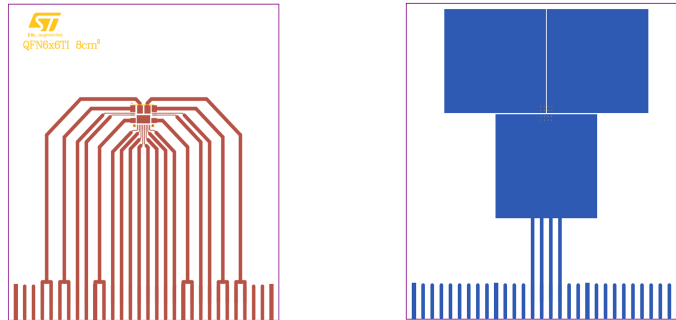


Figure 21. QFN 6x6 26+2L PCB, 6 layers (STPIN3P21, STSPIN3P22, STSPIN3P23)

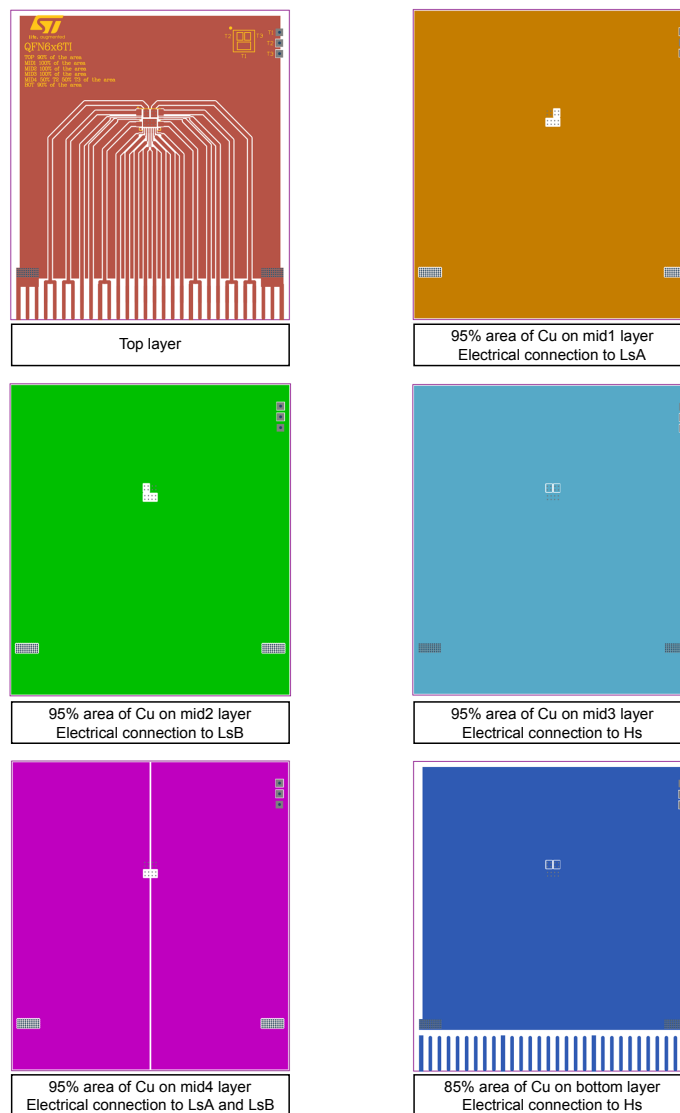
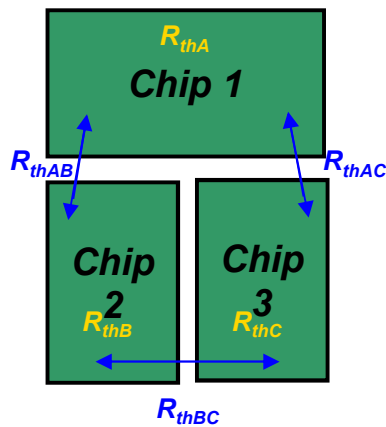


Table 18. PCB properties

Dimension	Value
Board	Double layer or six layers (STSPIN3P23) Six layers (STSPIN3P21, STSPIN3P22)
Board finish thickness	1.6 mm \pm 10%
Board dimension	78 mm x 86 mm
Board material	FR4
Cu thickness (outer layers)	0.070 mm
Cu thickness (inner layers)	0.035 mm
Thermal vias spaced on a	1.2 mm x 1.2 mm grid.
Vias pad clearance thickness	0.2 mm
Thermal via diameter	0.3 mm \pm 0.08 mm
Cu thickness on vias	0.025 mm

Figure 22. Chipset configuration

Table 19. $R_{thJ-Amb}$ vs Cu area dissipation

Thermal resistance ($^{\circ}$ C/W)	STSPIN3P23		STSPIN3P22	STSPIN3P21
	Cu 8 cm ² , 2 layers	6 layers	6 layers	6 layers
R_{thA}	42.2	24.3	24.8	25.2
$R_{thB} = R_{thC}$	49.4	28.2	28.5	29.0
$R_{thAB} = R_{thAC}$	19	10.5	10.1	10.1
R_{thBC}	19.8	11.2	11.2	11.2

Note: The $R_{thJ-PCB}$ is measured on 6 layers = 8.3 $^{\circ}$ C/W.

12.1.1 Thermal resistances definition

The values are defined according to the PCB heatsink area:

- $R_{thHS} = R_{thHSA} = R_{thHSB}$ = high-side chip thermal resistance junction to ambient (HSA or HSB in ON state)
- $R_{thLS} = R_{thLSA} = R_{thLSB}$ = low-side chip thermal resistance junction to ambient
- $R_{thHLS} = R_{thHSALS} = R_{thHSBLS}$ = mutual thermal resistance junction to ambient between high-side and low-side chips
- $R_{thLSL} = R_{thLSALS}$ = mutual thermal resistance junction to ambient between low-side chip.

Table 20. Thermal model for junction temperature calculation in steady-state conditions

Chip 1	Chip 2	Chip 3	T_{jchip1}	T_{jchip2}	T_{jchip3}
ON	OFF	ON	$P_{dchip1} \cdot R_{thA} + P_{dchip3} \cdot R_{thAC} + T_A$	$P_{dchip1} \cdot R_{thAB} + P_{dchip3} \cdot R_{thBC} + T_A$	$P_{dchip1} \cdot R_{thAC} + P_{dchip3} \cdot R_{thC} + T_A$
ON	ON	OFF	$P_{dchip1} \cdot R_{thA} + P_{dchip2} \cdot R_{thAB} + T_A$	$P_{dchip1} \cdot R_{thAB} + P_{dchip2} \cdot R_{thB} + T_A$	$P_{dchip1} \cdot R_{thAC} + P_{dchip2} \cdot R_{thBC} + T_A$
ON	OFF	OFF	$P_{dchip1} \cdot R_{thA} + T_A$	$P_{dchip1} \cdot R_{thAB} + T_A$	$P_{dchip1} \cdot R_{thAC} + T_A$
ON	ON	ON	$P_{dchip1} \cdot R_{thA} + (P_{dchip2} + P_{dchip3}) \cdot R_{thAB} + T_A$	$P_{dchip2} \cdot R_{thB} + P_{dchip1} \cdot R_{thAB} + P_{dchip3} \cdot R_{thBC} + T_A$	$P_{dchip1} \cdot R_{thAB} + P_{dchip2} \cdot R_{thBC} + P_{dchip3} \cdot R_{thC} + T_A$

12.1.2 Thermal characterization during transients

- $T_{hs} = P_{dhs} * Z_{hs} + Z_{hsls} * (P_{dlsA} + P_{dlsB}) + T_{Amb}$
- $T_{lsA} = P_{dlsA} * Z_{ls} + P_{dhs} * Z_{hsls} + P_{dlsB} * Z_{lsls} + T_{Amb}$
- $T_{lsB} = P_{dlsB} * Z_{ls} + P_{dhs} * Z_{hsls} + P_{dlsA} * Z_{lsls} + T_{Amb}$

Figure 23. HSD thermal impedance junction ambient single pulse (STSPIN3P23)

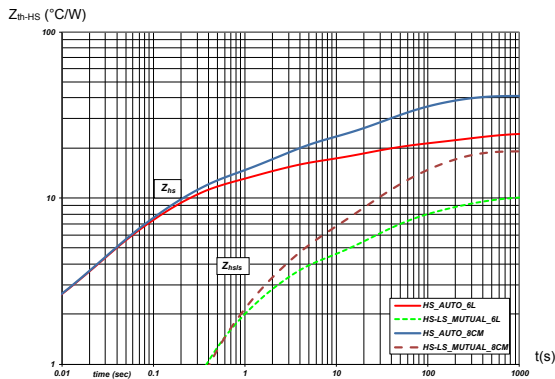


Figure 24. LSD thermal impedance junction ambient single pulse (STSPIN3P23)

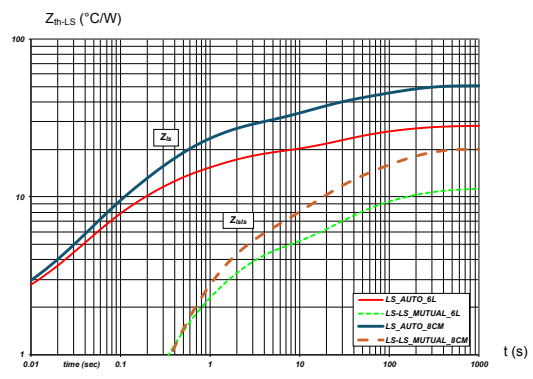


Figure 25. HSD thermal impedance junction ambient single pulse (STSPIN3P22)

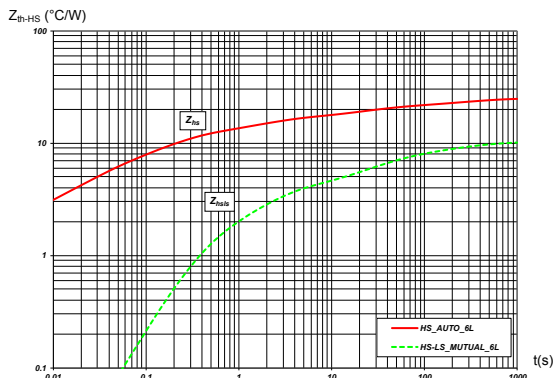


Figure 26. LSD thermal impedance junction ambient single pulse (STSPIN3P22)

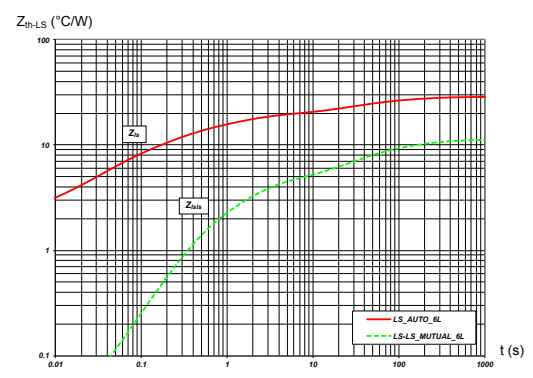


Figure 27. HSD thermal impedance junction ambient single pulse (STSPIN3P22)

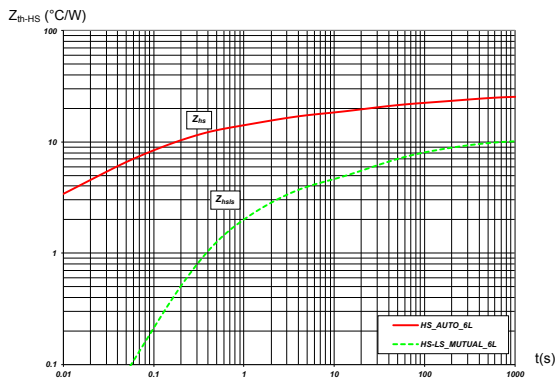


Figure 28. LSD thermal impedance junction ambient single pulse (STSPIN3P22)

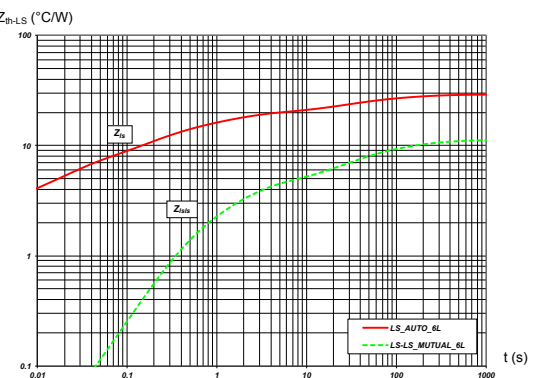
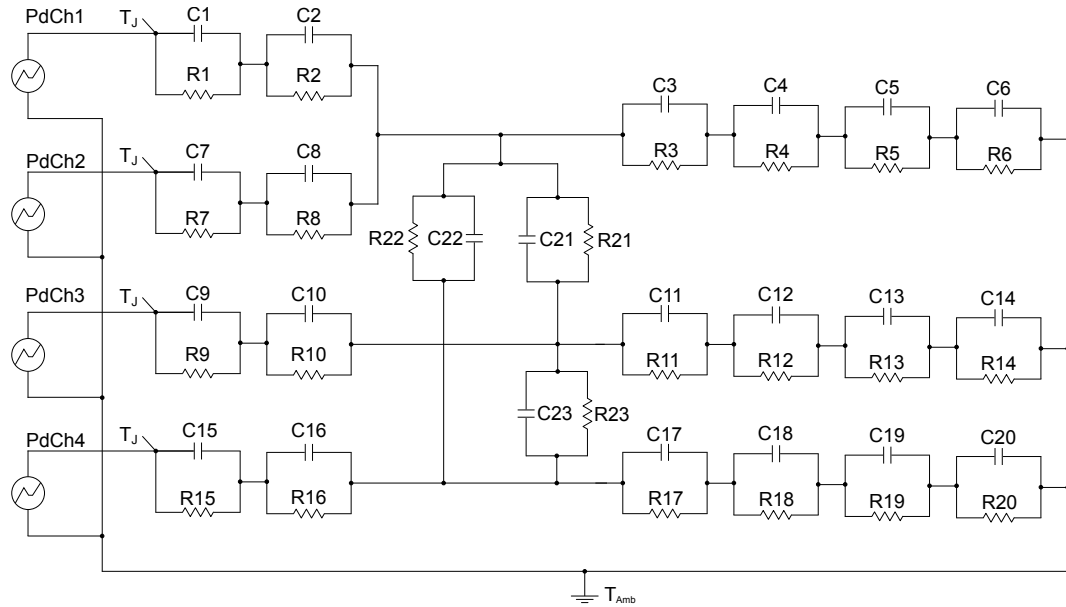


Figure 29. Thermal fitting model



Note: *The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protections (power limitation or thermal cycling during thermal shutdown) are not triggered.*

Table 21. Thermal parameters

Thermal parameter	STSPIN3P23		STSPIN3P22	STSPIN3P21
	8 cm ² , 2 layers	6 layers	6 layers	6 layers
R1 = R7 (°C/W)	1.35	1.35	1.55	1.8
R2 = R8 (°C/W)	2.8	2.5	2.8	3
R3 (°C/W)	8.5	8.5	8.5	8.5
R4 (°C/W)	13	8.5	8.5	8.5
R5 (°C/W)	20	9	9	9
R6 (°C/W)	21	9.5	9.5	9.5
R9 = R15 (°C/W)	1.7	1.7	1.9	2.2
R10 = R16 (°C/W)	3.2	3.2	3.3	3.5
R11 = R17 (°C/W)	7.5	7.5	7.5	7.5
R12 = R18 (°C/W)	25	14	14	14
R13 = R19 (°C/W)	31	13	13	13
R14 = R20 (°C/W)	31	14	14	14
R21 = R22 (°C/W)	90	50	50	50
R23 (°C/W)	115	47	47	47
C1 = C7 (W·s/°C)	0.001	0.001	0.0012	0.0011
C2 = C8 (W·s/°C)	0.01	0.01	0.007	0.007
C3 (W·s/°C)	0.022	0.022	0.022	0.022
C4 (W·s/°C)	0.2	0.2	0.2	0.2
C5 (W·s/°C)	2	2.3	2.3	2.3
C6 (W·s/°C)	7.5	40	40	40
C9 = C15 (W·s/°C)	0.0007	0.0007	0.0007	0.00055
C10 = C16 (W·s/°C)	0.013	0.013	0.01	0.005
C11 = C17 (W·s/°C)	0.03	0.03	0.03	0.03
C12 = C18 (W·s/°C)	0.04	0.1	0.1	0.1
C13 = C19 (W·s/°C)	0.5	2.2	2.2	2.2
C14 = C20 (W·s/°C)	4	8	8	8
C21 = C22 (W·s/°C)	0.0002	0.0005	0.0005	0.0005
C23 (W·s/°C)	0.00015	0.0005	0.0011	0.0011

13 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

13.1 QFN 6x6 triple pad 26+2L package information

Figure 30. QFN 6x6 triple pad 26+2L package outline

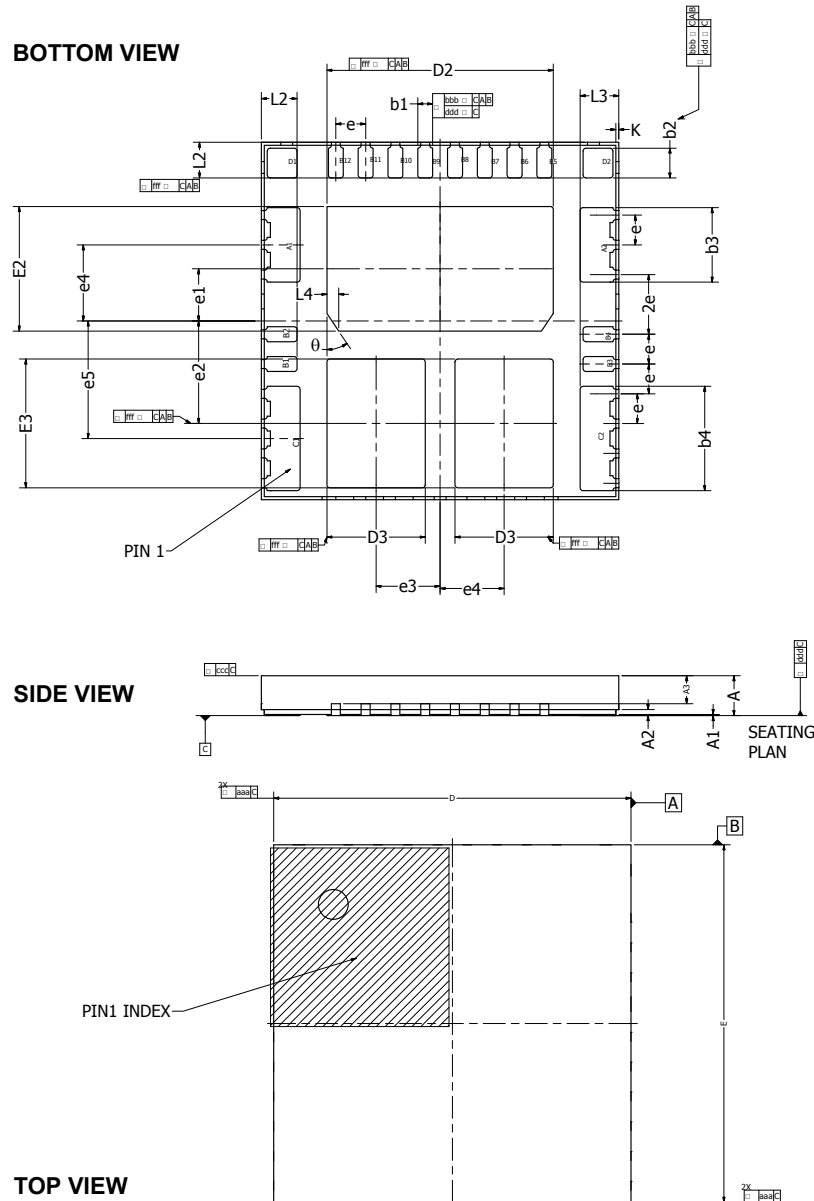


Figure 31. QFN 6x6 triple pad 26+2L package sections

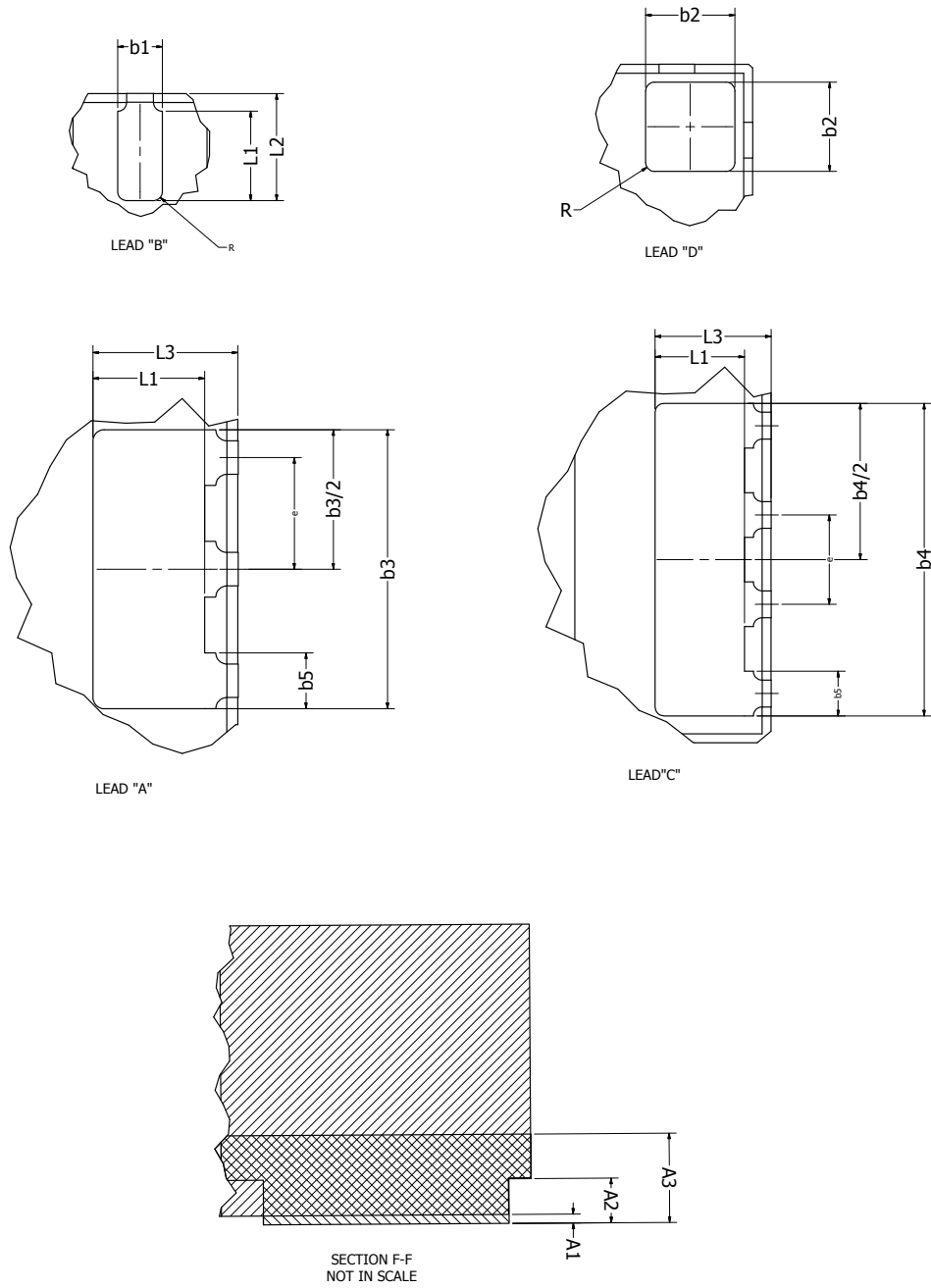


Table 22. QFN 6x6 triple pad 26+2L mechanical data

Symbol	Millimeters		
	Min.	Typ.	Max.
A	0.80	0.90	1.00
A1	0.00		0.05
A2	0.10		
A3	0.20 REF.		
b1	0.20	0.25	0.30
b2	0.45	0.50	0.55
b3	1.15	1.25	1.35
b4	1.65	1.75	1.85
b5	0.20	0.25	0.30
D	6.00 BSC		
E	6.00 BSC		
D2	3.70	3.75	3.80
D3	1.55	1.60	1.65
E2	2.00	2.05	2.10
E3	2.05	2.10	2.15
e	0.50 REF		
e1	0.88 REF		
e2	1.72 REF		
e3	1.08 REF		
e4	1.28 REF		
e5	1.97 REF		
L1	0.45	0.50	0.55
L2	0.55	0.60	0.65
L3	0.65	0.70	0.75
L4	0.15	0.20	0.25
θ	34°		
N	26 + 2		
R	0.05		

Table 23. QFN 6x6 triple pad 26+2L tolerance of form and position

Symbol	Millimeters
aaa	0.15
bbb	0.10
ccc	0.10
ddd	0.05
eee	0.08
fff	0.10

14 Ordering information

Table 24. Order code

Order code	Package	Package marking	Packing
STSPIN3P21TR	QFN 6x6 triple pad 26+2L	STSPIN3P21	Tape and reel
STSPIN3P22TR	QFN 6x6 triple pad 26+2L	STSPIN3P22	Tape and reel
STSPIN3P23TR	QFN 6x6 triple pad 26+2L	STSPIN3P23	Tape and reel

Revision history

Table 25. Document revision history

Date	Revision	Changes
24-Apr-2026	1	Initial release.

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